



MEASUREMENT REPORT
FCC Part 90

Applicant:

Samsung Electronics Co., Ltd.
129, Samsung-ro,
Yeongtong-gu, Suwon-si
Gyeonggi-do, 16677, Korea

Date of Testing:

12/4/2015-1/15/2016

Test Site/Location:

PCTEST Lab., Columbia, MD, USA

Test Report Serial No.:

0Y1512032049.A3L

FCC ID:

A3LSMJ700P

APPLICANT:

SAMSUNG ELECTRONICS CO., LTD.

Applicant Type:

Certification

FCC Classification:

PCS Licensed Transmitter Held to Ear (PCE)

FCC Rule Part:

§90.691

Test Procedure(s):

KDB 971168 D01 v02r02

EUT Type:

Portable Handset

Model(s):

SM-J700P

Test Device Serial No.:

identical prototype [S/N: 3DEC-2, 3DEC-5]

Mode	Tx Frequency (MHz)	Emission Designator	Cond. PWR	
			Max. Power (W)	Max. Power (dBm)
CDMA800 (BC10)	817.9 - 823.1	1M28F9W	0.316	25.00
LTE Band 26	814.7 - 823.3	1M08G7D	0.242	23.84
LTE Band 26	814.7 - 823.3	1M08W7D	0.200	23.00
LTE Band 26	815.5 - 822.5	2M70G7D	0.243	23.85
LTE Band 26	815.5 - 822.5	2M69W7D	0.196	22.92
LTE Band 26	816.5 - 821.5	4M51G7D	0.245	23.89
LTE Band 26	816.5 - 821.5	4M51W7D	0.196	22.93
LTE Band 26	819	9M00G7D	0.245	23.89
LTE Band 26	819	8M98W7D	0.200	23.00

This equipment has been shown to be capable of compliance with the applicable technical standards as indicated in the measurement report and was tested in accordance with the measurement procedures specified in §2.947. Test results reported herein relate only to the item(s) tested.

I attest to the accuracy of data. All measurements reported herein were performed by me or were made under my supervision and are correct to the best of my knowledge and belief. I assume full responsibility for the completeness of these measurements and vouch for the qualifications of all persons taking them.


Randy Ortanez
President

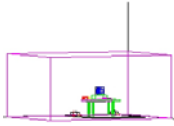


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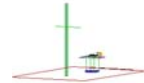
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FCC Part 90 LTE Band 26 and BC10 CDMA

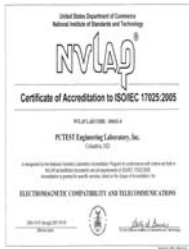
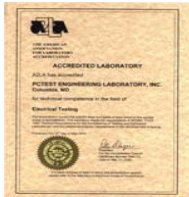


§2.1033 General Information

APPLICANT: Samsung Electronics Co., Ltd.
APPLICANT ADDRESS: 129, Samsung-ro,
 Yeongtong-gu, Suwon-si, Gyeonggi-do, 16677, Korea
TEST SITE: PCTEST ENGINEERING LABORATORY, INC.
TEST SITE ADDRESS: 7185 Oakland Mills Road, Columbia, MD 21045 USA
BASE MODEL: SM-J700P
FCC CLASSIFICATION: PCS Licensed Transmitter Held to Ear (PCE)
MODE: CDMA / EvDO / LTE
FREQUENCY TOLERANCE: $\pm 0.00025\%$ (2.5 ppm)
Test Device Serial No.: 3DEC-2, 3DEC-5 ☐ Production ☒ Pre-Production ☐ Engineering
DATE(S) OF TEST: 12/4/2015-1/15/2016
TEST REPORT S/N: 0Y1512032049.A3L

Test Facility / Accreditations

Measurements were performed at PCTEST Engineering Lab. located in Columbia, MD 21046, U.S.A.



- PCTEST facility is an FCC registered (PCTEST Reg. No. 159966) test facility with the site description report on file and has met all the requirements specified in Section 2.948 of the FCC Rules.
- PCTEST Lab is accredited to ISO 17025 by U.S. National Institute of Standards and Technology (NIST) under the National Voluntary Laboratory Accreditation Program (NVLAP Lab code: 100431-0) in EMC, FCC and Telecommunications.
- PCTEST Lab is accredited to ISO 17025-2005 by the American Association for Laboratory Accreditation (A2LA) in Specific Absorption Rate (SAR) testing, Hearing Aid Compatibility (HAC) testing, CTIA Test Plans, and wireless testing for FCC.
- PCTEST Lab is a recognized U.S. Conformity Assessment Body (CAB) in EMC and R&TTE (n.b. 0982) under the U.S.-EU Mutual Recognition Agreement (MRA).
- PCTEST TCB is a Telecommunication Certification Body (TCB) accredited to ISO/IEC Guide 65 by the American National Standards Institute (ANSI) in all scopes of FCC Rules.
- PCTEST is a CTIA Authorized Test Laboratory (CATL) for AMPS, CDMA, and EvDO wireless devices and for Over-the-Air (OTA) Antenna Performance testing for AMPS, CDMA, GSM, GPRS, EGPRS, UMTS (W-CDMA), CDMA 1xEVDO, and CDMA 1xRTT.

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1.0 INTRODUCTION

1.1 Scope

Measurement and determination of electromagnetic emissions (EME) of radio frequency devices including intentional and/or unintentional radiators for compliance with the technical rules and regulations of the Federal Communications Commission and the Industry Canada Certification and Engineering Bureau.

1.2 Testing Facility

The map below shows the location of the PCTEST LABORATORY, its proximity to the FCC Laboratory, the Columbia vicinity, the Baltimore-Washington Intern't'l (BWI) airport, the city of Baltimore and the Washington, DC area. (See Figure 1-1).

These measurement tests were conducted at the PCTEST Engineering Laboratory, Inc. facility located at 7185 Oakland Mills Road, Columbia, MD 21046. The site coordinates are 39° 10'23" N latitude and 76° 49'50" W longitude. The facility is 0.4 miles North of the FCC laboratory, and the ambient signal and ambient signal strength are approximately equal to those of the FCC laboratory. The detailed description of the measurement facility was found to be in compliance with the requirements of § 2.948 according to ANSI C63.4-2014 on January 22, 2015.

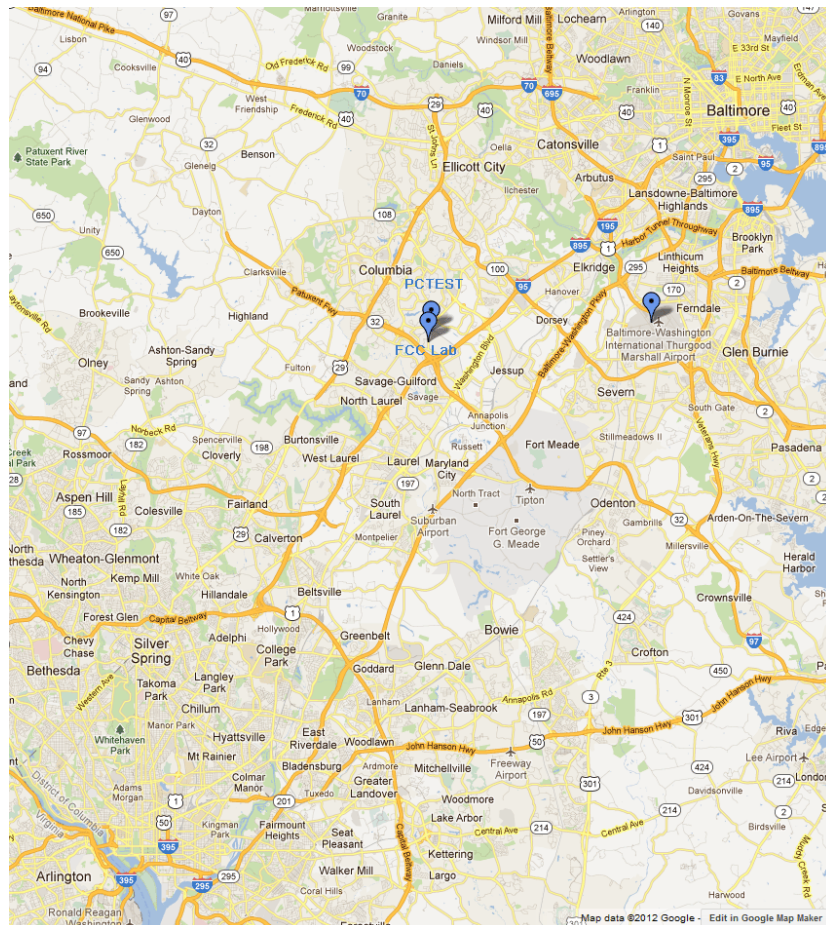


Figure 1-1. Map of the Greater Baltimore and Metropolitan Washington, D.C. area

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2.0 PRODUCT INFORMATION

2.1 Equipment Description

The Equipment Under Test (EUT) is the **Samsung Portable Handset FCC ID: A3LSMJ700P**. The test data contained in this report pertains only to the emissions due to the EUT's licensed transmitters that operate under the provisions of Part 90.691.

2.2 Device Capabilities

This device contains the following capabilities:

850/1900 CDMA/EVDO (BC0, BC1, BC10), 850/1900 GSM/GPRS/EDGE, 850/1900 WCDMA/HSPA, Multi-band LTE, 802.11b/g/n WLAN, 802.11a/n UNII, Bluetooth (1x, EDR, LE), NFC, ANT+

2.3 Test Configuration

The Samsung Portable Handset FCC ID: A3LSMJ700P was tested per the guidance of ANSI/TIA-603-C-2004 and KDB 971168 D01 v02r02. See Section 7.0 of this test report for a description of the radiated and antenna port conducted emissions tests.

2.4 EMI Suppression Device(s)/Modifications

No EMI suppression device(s) were added and no modifications were made during testing.

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3.0 DESCRIPTION OF TESTS

3.1 Evaluation Procedure

The measurement procedures described in the document titled “Land Mobile FM or PM – Communications Equipment – Measurements and Performance Standards” (ANSI/TIA-603-C-2004) and “Procedures for Compliance Measurement of the Fundamental Emission Power of Licensed Wideband (> 1 MHz) Digital Transmission Systems” (KDB 971168 D01 v02r02) were used in the measurement of the **Samsung Portable Handset FCC ID: A3LSMJ700P**.

3.2 Occupied Bandwidth

§2.1049

The occupied bandwidth, that is the frequency bandwidth such that, below its lower and above its upper frequency limits, the mean powers radiated are each equal to 0.5 percent of the total mean power radiated by a given emission shall be measured. The spectrum analyzers’ “occupied bandwidth” measurement function was used to record the occupied bandwidth in accordance with KDB 971168.

3.3 Spurious and Harmonic Emissions at Antenna Terminal

§2.1051, §90.691

The level of the carrier and the various conducted spurious and harmonic frequencies is measured by means of a calibrated spectrum analyzer. The spectrum is scanned from the lowest frequency generated in the equipment up to a frequency including its 10th harmonic.

Out-of-band emission requirement shall apply only to the “outer” channels included in an EA license and to spectrum adjacent to interior channels used by incumbent licensees. The emission limits are as follows:

For any frequency removed from the EA licensee's frequency block by up to and including 37.5 kHz, the power of any emission shall be attenuated below the transmitter power (P) in watts by at least $116 \log_{10}(f/6.1)$ decibels or $50 + 10 \log_{10}(P)$ decibels or 80 decibels, whichever is the lesser attenuation, where f is the frequency removed from the center of the outer channel in the block in kilohertz and where f is greater than 12.5 kHz.

For any frequency removed from the EA licensee's frequency block greater than 37.5 kHz, the power of any emission shall be attenuated below the transmitter power (P) in watts by at least $43 + 10 \log_{10}(P)$ decibels or 80 decibels, whichever is the lesser attenuation, where f is the frequency removed from the center of the outer channel in the block in kilohertz and where f is greater than 37.5 kHz.

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3.4 Radiated Power and Radiated Spurious Emissions

§2.1053, §90.635, §90.691

The radiated test facilities consisted of an indoor 3 meter semi-anechoic chamber used for final measurements and exploratory measurements, when necessary. The measurement area is contained within the semi-anechoic chamber which is shielded from any ambient interference. The test site inside the chamber is a 6m x 5.2m elliptical, obstruction-free area in accordance with Clause 5, Figure 5.7 of ANSI C63.4-2009. For measurements above 1GHz absorbers are arranged on the floor between the turn table and the antenna mast in such a way so as to maximize the reduction of reflections. For measurements below 1GHz, the absorbers are removed. An ETS Lindgren Model 2188 raised turntable is used for radiated measurement. It is a continuously rotatable, remote-controlled, metallic turntable and 2 meters (6.56 ft.) in diameter. The turn table is flush with the raised floor of the chamber in order to maintain its function as a ground plane. A 78cm high PVC support structure is placed on top of the turntable. A ¾" (~1.9cm) sheet of high density polyethylene is used as the table top and is placed on top of the PVC supports to bring the total height of the table to 80cm.

The equipment under test was transmitting while connected to its integral antenna and is placed on a wooden turntable 80cm above the ground plane and 3 meters from the receive antenna. The receive antenna height is adjusted between 1 and 4 meter height, the turntable is rotated through 360 degrees, and the EUT is manipulated through all orthogonal planes representative of its typical use to achieve the highest reading on the receive spectrum analyzer. Radiated power levels are also investigated with the receive antenna horizontally and vertically polarized. The maximized power level is recorded using the spectrum analyzer "Channel Power" function with the integration band set to the emissions' occupied bandwidth, a RMS detector, RBW = 100kHz, VBW = 300kHz, and a 1 second sweep time over a minimum of 10 sweeps, per the guidelines of KDB 971168.

Per the guidance of ANSI/TIA-603-C-2004, a half-wave dipole is then substituted in place of the EUT. For emissions above 1GHz, a horn antenna is substituted in place of the EUT. The substitute antenna is driven by a signal generator with the level of the signal generator being adjusted to obtain the same receive spectrum analyzer level previously recorded from the spurious emission from the EUT. The power of the emission is calculated using the following formula:

$$P_d \text{ [dBm]} = P_g \text{ [dBm]} - \text{cable loss [dB]} + \text{antenna gain [dBd/dBi]}$$

Where, P_d is the dipole equivalent power, P_g is the generator output into the substitution antenna, and the antenna gain is the gain of the substitute antenna used relative to either a half-wave dipole (dBd) or an isotropic source (dBi). The substitute level is equal to $P_g \text{ [dBm]} - \text{cable loss [dB]}$.

The calculated P_d levels are then compared to the absolute spurious emission limit of -13dBm which is equivalent to the required minimum attenuation of $43 + 10\log_{10}(\text{Power [Watts]})$ specified in 90.691.

For fundamental radiated power measurements, the guidance of KDB 971168 is used to record the EUT power level that is subsequently matched via the aforementioned substitution method given in ANSI/TIA-603-C-2004.

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3.5 Frequency Stability / Temperature Variation

§2.1055, 90.213(a)

Frequency stability testing is performed in accordance with the guidelines of ANSI/TIA-603-C-2004. The frequency stability of the transmitter is measured by:

- a.) **Temperature:** The temperature is varied from -30°C to +50°C in 10°C increments using an environmental chamber.
- b.) **Primary Supply Voltage:** The primary supply voltage is varied from 85% to 115% of the nominal value for non hand-carried battery and AC powered equipment. For hand-carried, battery-powered equipment, primary supply voltage is reduced to the battery operating end point which shall be specified by the manufacturer.

Specification – For Part 90.213, the frequency stability of the transmitter shall be maintained within $\pm 0.00025\%$ (± 2.5 ppm) of the center frequency.

Time Period and Procedure:

1. The carrier frequency of the transmitter is measured at room temperature (20°C to provide a reference).
2. The equipment is turned on in a “standby” condition for fifteen minutes before applying power to the transmitter. Measurement of the carrier frequency of the transmitter is made within one minute after applying power to the transmitter.
3. Frequency measurements are made at 10°C intervals ranging from -30°C to +50°C. A sufficient stabilization period at each temperature shall be used prior to each frequency requirement.

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4.0 MEASUREMENT UNCERTAINTY

The measurement uncertainties shown below were calculated in accordance with the requirements of ANSI C63.4-2014. All measurement uncertainty values are shown with a coverage factor of $k = 2$ to indicate a 95% level of confidence. The measurement data shown herein meets or exceeds the U_{CISPR} measurement uncertainty values specified in CISPR 16-4-2 and, thus, can be compared directly to specified limits to determine compliance.

Contribution	Expanded Uncertainty ($\pm$ dB)
Conducted Bench Top Measurements	1.13
Radiated Disturbance (<1GHz)	4.98
Radiated Disturbance (>1GHz)	5.07
Radiated Disturbance (>18GHz)	5.09

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5.0 TEST EQUIPMENT CALIBRATION DATA

Test Equipment Calibration is traceable to the National Institute of Standards and Technology (NIST).

Manufacturer	Model	Description	Cal Date	Cal Interval	Cal Due	Serial Number
-	LTX1	Licensed Transmitter Cable Set	4/16/2015	Annual	4/16/2016	LTX1
-	RE1	Radiated Emissions Cable Set (UHF/EHF)	4/28/2015	Annual	4/28/2016	RE1
Agilent	8447D	Broadband Amplifier	6/12/2015	Annual	6/12/2016	1937A03348
Agilent	E5515C	Wireless Communications Test Set	N/A			GB46110872
Agilent	N9020A	MXA Signal Analyzer	11/5/2015	Annual	11/5/2016	US46470561
Agilent	E5515C	Wireless Communications Test Set	3/19/2014	Biennial	3/19/2016	GB45360985
Agilent	N9030A	PXA Signal Analyzer (44GHz)	3/24/2015	Annual	3/24/2016	MY52350166
Com-Power	AL-130	9kHz - 30MHz Loop Antenna	7/30/2015	Biennial	7/30/2017	121034
Emco	3115	Horn Antenna (1-18GHz)	1/30/2014	Biennial	1/30/2016	9704-5182
Espec	ESX-2CA	Environmental Chamber	3/17/2015	Annual	3/17/2016	17620
ETS Lindgren	3117	1-18 GHz DRG Horn (Medium)	4/8/2014	Biennial	4/8/2016	125518
ETS Lindgren	3160-09	18-26.5 GHz Standard Gain Horn	6/17/2014	Biennial	6/17/2016	135427
K & L	13SH10-1000/U1000	N Type High Pass Filter	7/18/2015	Annual	7/18/2016	13SH10-1000/U1000-1
Rhode & Schwarz	TS-PR18	Pre-Amplifier	3/5/2015	Annual	3/5/2016	101622
Rohde & Schwarz	CMW500	Radio Communication Tester	10/13/2015	Annual	10/13/2016	100976
Rohde & Schwarz	TS-PR18	1-18 GHz Pre-Amplifier	3/5/2015	Annual	3/5/2016	100071
Rohde & Schwarz	TS-PR26	18-26.5 GHz Pre-Amplifier	3/3/2015	Annual	3/3/2016	100040
Rohde & Schwarz	ESU26	EMI Test Receiver (26.5GHz)	3/12/2015	Annual	3/12/2016	100342
Rohde & Schwarz	CMW500	Radio Communication Tester	10/21/2015	Annual	10/21/2016	102060
Rohde & Schwarz	ESU40	EMI Test Receiver (40GHz)	7/17/2015	Annual	7/17/2016	100348
Schwarzbeck	UHA 9105	Dipole Antenna (400 - 1GHz) Rx	2/21/2014	Biennial	2/21/2016	9105-2404
Sunol	JB5	Bi-Log Antenna (30M - 5GHz)	1/28/2014	Biennial	1/28/2016	A051107

Table 5-1. Test Equipment

Notes:

1. Equipment with a calibration date of "N/A" shown in this list was not used to make direct calibrated measurements.

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6.0 SAMPLE CALCULATIONS

Emission Designator

Emission Designator = 1M25F9W

CDMA BW = 1.25 MHz

F = Frequency Modulation

9 = Composite Digital Info

W = Combination (Audio/Data) (Measured at the 99.75% power bandwidth)

Spurious Radiated Emission – BC10

Example: Channel 476 CDMA BC10 Mode 3rd Harmonic (2453.70MHz)

The average spectrum analyzer reading at 3 meters with the EUT on the turntable was –81.0 dBm. The gain of the substituted antenna is 8.1 dBi. The signal generator connected to the substituted antenna terminals is adjusted to produce a reading of –81.0 dBm on the spectrum analyzer. The loss of the cable between the signal generator and the terminals of the substituted antenna is 2.0 dB at 2453.70 MHz. So 6.1 dB is added to the signal generator reading of –30.9 dBm yielding –24.80 dBm. The fundamental EIRP was 25.501 dBm so this harmonic was 25.501 dBm – (–24.80) = 50.3 dBc.

Emission Designator

QPSK Modulation

Emission Designator = 8M62G7D

LTE BW = 8.62 MHz

G = Phase Modulation

7 = Quantized/Digital Info

D = Data transmission, telemetry, telecommand

16QAM Modulation

Emission Designator = 8M45W7D

LTE BW = 8.45 MHz

W = Amplitude/Angle Modulated

7 = Quantized/Digital Info

D = Data transmission, telemetry, telecommand

Spurious Radiated Emission – LTE Band

Example: Middle Channel LTE Mode 2nd Harmonic (1564 MHz)

The average spectrum analyzer reading at 3 meters with the EUT on the turntable was –81.0 dBm. The gain of the substituted antenna is 8.1 dBi. The signal generator connected to the substituted antenna terminals is adjusted to produce a reading of –81.0 dBm on the spectrum analyzer. The loss of the cable between the signal generator and the terminals of the substituted antenna is 2.0 dB at 1564 MHz. So 6.1 dB is added to the signal generator reading of –30.9 dBm yielding –24.80 dBm. The fundamental EIRP was 25.501 dBm so this harmonic was 25.501 dBm – (–24.80).

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7.0 TEST RESULTS

7.1 Summary

Company Name: Samsung Electronics Co., Ltd.
 FCC ID: A3LSMJ700P
 FCC Classification: PCS Licensed Transmitter Held to Ear (PCE)
 Mode(s): CDMA / EvDO / LTE
 Band: Band Class 10 / Band 26

FCC Part Section(s)	Test Description	Test Limit	Test Condition	Test Result	Reference
TRANSMITTER MODE (TX)					
2.1049	Occupied Bandwidth	N/A	CONDUCTED	PASS	Section 7.2
2.1051 90.691	Conducted Band Edge / Spurious Emissions	> 43 + log ₁₀ (P[Watts]) for all out-of-band emissions except > 50 + 10log ₁₀ (P[Watts]) at Band Edge and for all out-of-band emissions within 37.5kHz of Block Edge		PASS	Sections 7.3, 7.4
2.1055 90.213	Frequency Stability	< 2.5 ppm		PASS	Section 7.7
2.1046 90.635	Conducted Power	< 100 Watts		PASS	Section 7.5
2.1053 90.691	Radiated Spurious Emissions	> 43 + log ₁₀ (P[Watts]) for all out-of-band emissions except > 50 + 10log ₁₀ (P[Watts]) at Band Edge and for all out-of-band emissions within 37.5kHz of Block Edge	RADIATED	PASS	Section 7.6

Table 7-1. Summary of Test Results

Notes:

- 1) All modes of operation and data rates were investigated. The test results shown in the following sections represent the worst case emissions.
- 2) The analyzer plots shown in Section 7.0 were taken with a correction table loaded into the analyzer. The correction table was used to account for the losses of the cables, directional couplers, and attenuators used as part of the system to maintain a link between the call box and the EUT at all frequencies of interest.
- 3) All antenna port conducted emissions testing was performed on a test bench with the antenna port of the EUT connected to the spectrum analyzer through calibrated cables, attenuators, and couplers.
- 4) For conducted spurious emissions, automated test software was used to measure emissions and capture the corresponding plots necessary to show compliance. The measurement software utilized is PCTEST "2G/3G Automation," Version 3.2.

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7.2 Occupied Bandwidth

§2.1049

Test Overview

The occupied bandwidth, that is the frequency bandwidth such that, below its lower and above its upper frequency limits, the mean powers radiated are each equal to 0.5 percent of the total mean power radiated by a given emission shall be measured. All modes of operation were investigated and the worst case configuration results are reported in this section.

Test Procedure Used

KDB 971168 D01 v02r02 – Section 4.2

Test Settings

1. The signal analyzer's automatic bandwidth measurement capability was used to perform the 99% occupied bandwidth and the 26dB bandwidth. The bandwidth measurement was not influenced by any intermediate power nulls in the fundamental emission.
2. RBW = 1 – 5% of the expected OBW
3. VBW $\geq 3 \times$ RBW
4. Detector = Peak
5. Trace mode = max hold
6. Sweep = auto couple
7. The trace was allowed to stabilize
8. If necessary, steps 2 – 7 were repeated after changing the RBW such that it would be within 1 – 5% of the 99% occupied bandwidth observed in Step 7

Test Setup

The EUT and measurement equipment were set up as shown in the diagram below.

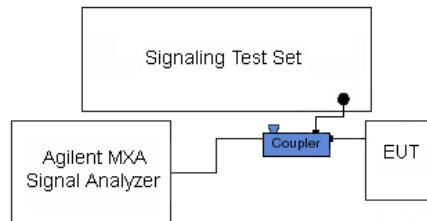
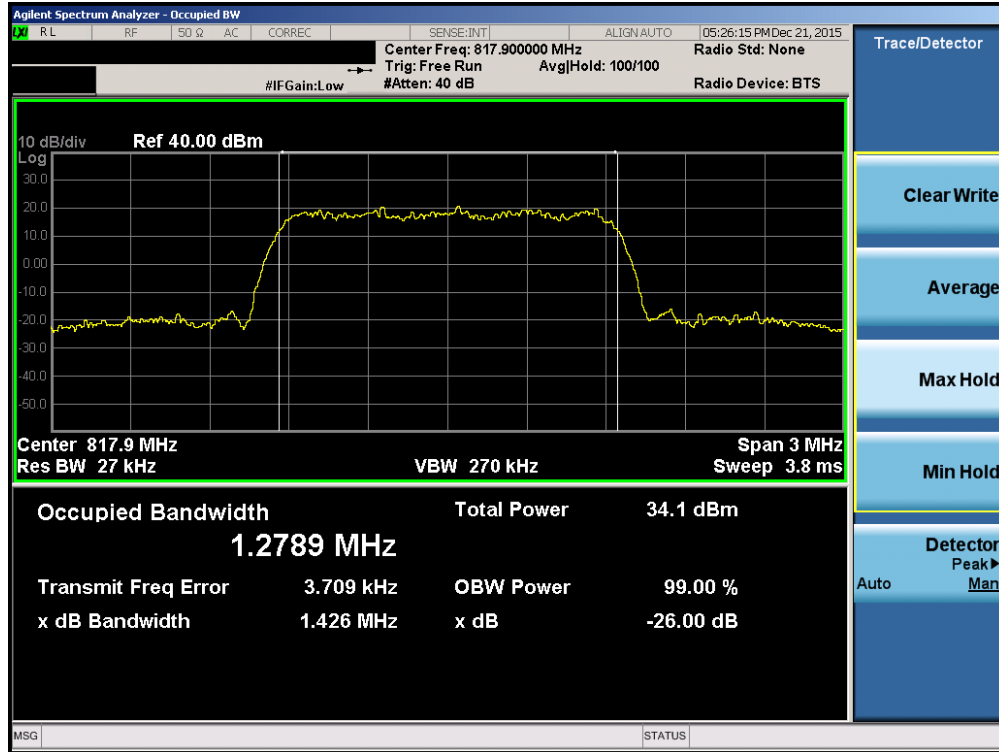


Figure 7-1. Test Instrument & Measurement Setup

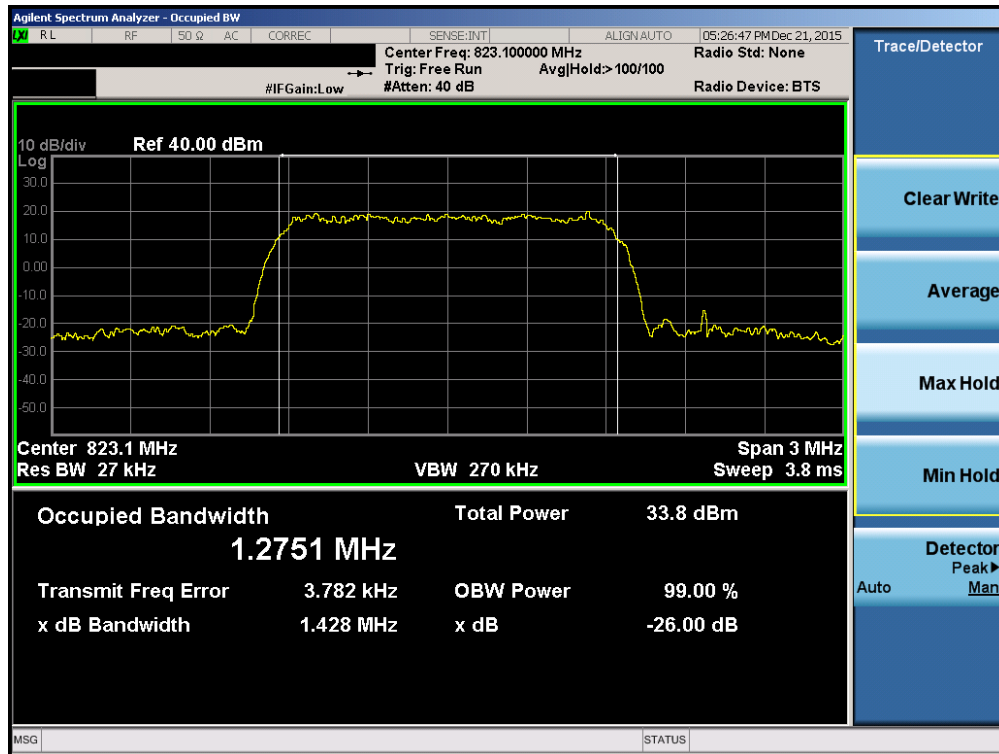
Test Notes

None.

FCC ID: A3LSMJ700P	PCTEST ENGINEERING LABORATORY, INC.	Part 90 CDMA / EvDO / LTE MEASUREMENT REPORT CERTIFICATION	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1512032049.A3L	Test Dates: 12/4/2015-1/15/2016	EUT Type: Portable Handset		Page 13 of 40

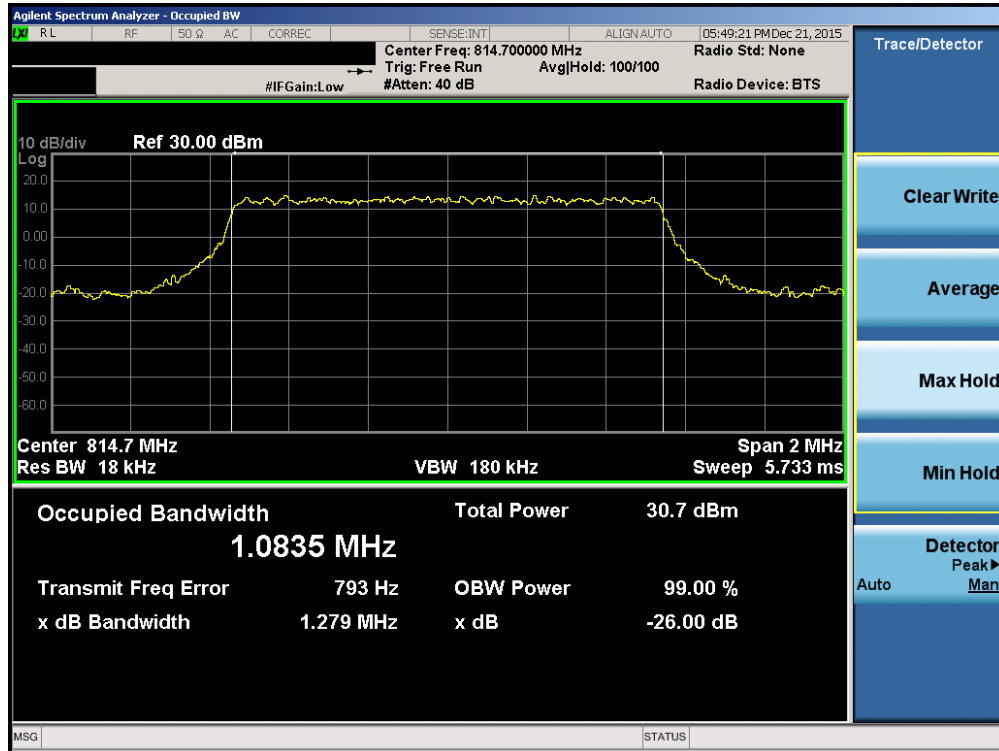


Plot 7-1. Occupied Bandwidth Plot (CDMA Ch. 476)

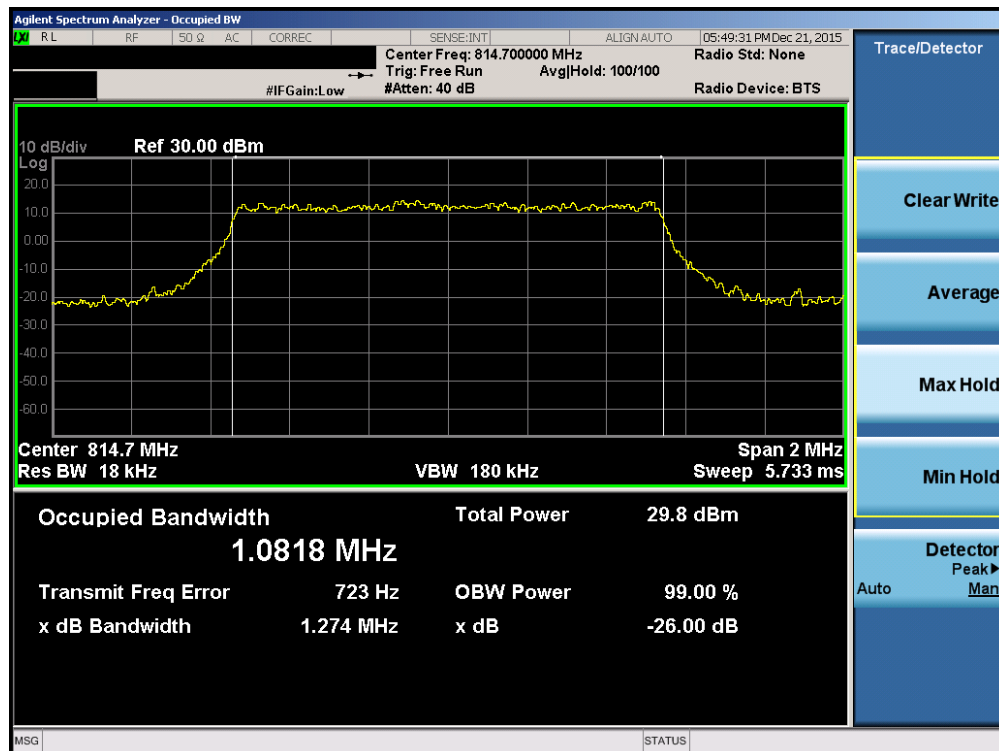


Plot 7-2. Occupied Bandwidth Plot (CDMA Ch. 684)

FCC ID: A3LSMJ700P	PCTEST ENGINEERING LABORATORY, INC.	Part 90 CDMA / EvDO / LTE MEASUREMENT REPORT CERTIFICATION	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1512032049.A3L	Test Dates: 12/4/2015-1/15/2016	EUT Type: Portable Handset		Page 14 of 40

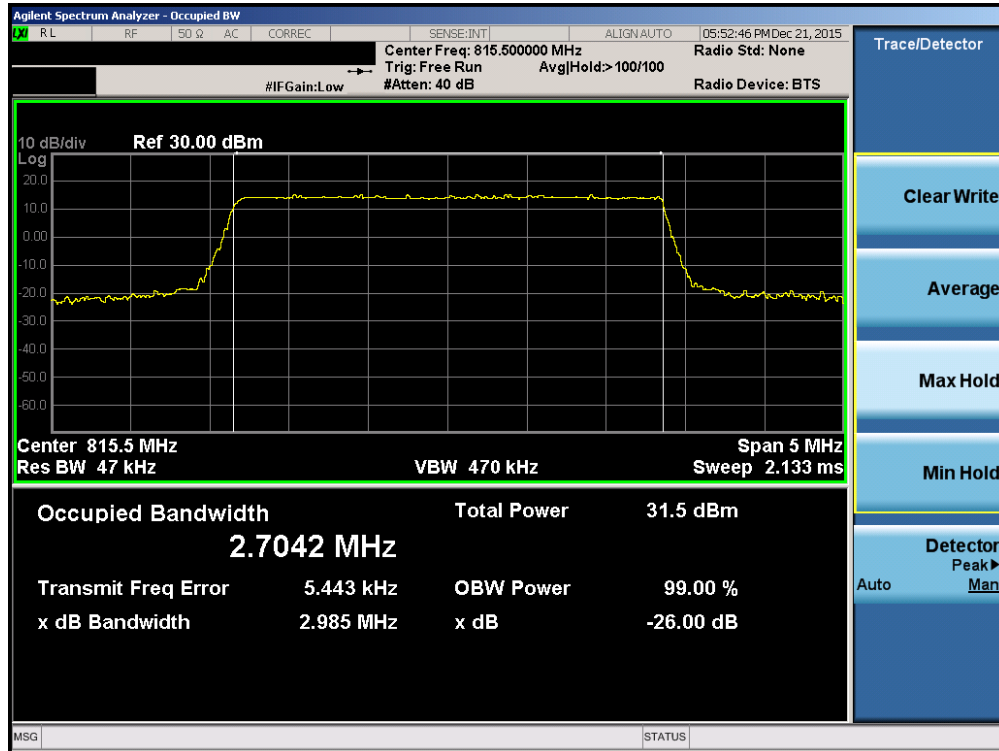


Plot 7-3. Occupied Bandwidth Plot (LTE Band 26 1.4MHz QPSK – RB Size 6– Low Channel)

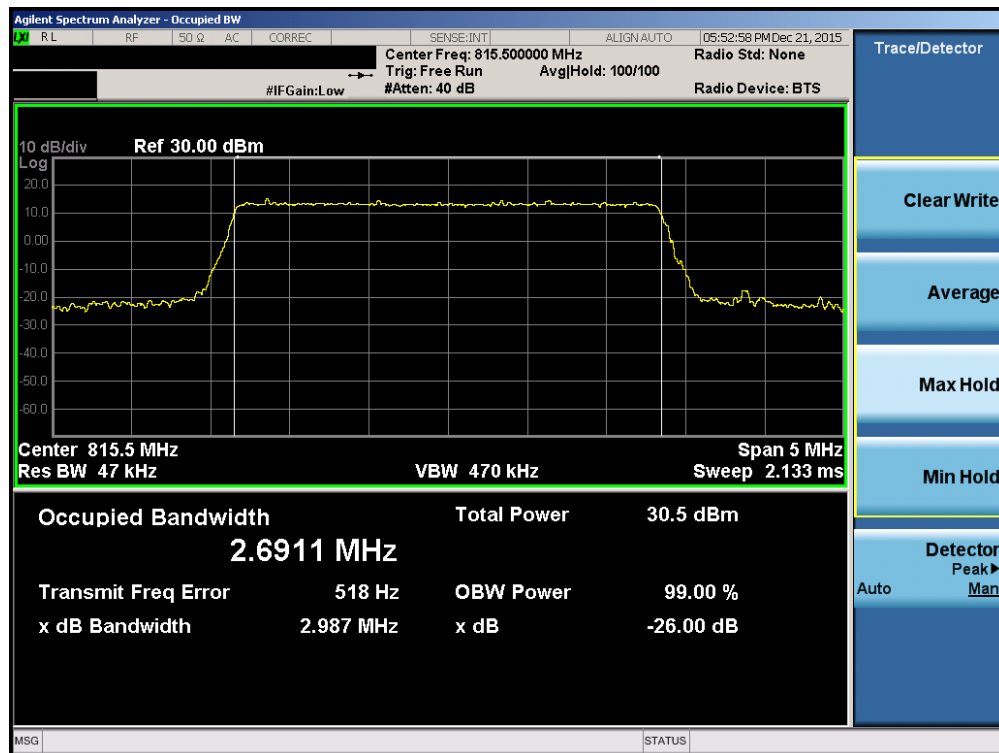


Plot 7-4. Occupied Bandwidth Plot (LTE Band 26 1.4MHz 16-QAM – RB Size 6– Low Channel)

FCC ID: A3LSMJ700P	PCTEST ENGINEERING LABORATORY, INC.	Part 90 CDMA / EvDO / LTE MEASUREMENT REPORT CERTIFICATION	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1512032049.A3L	Test Dates: 12/4/2015-1/15/2016	EUT Type: Portable Handset		Page 15 of 40

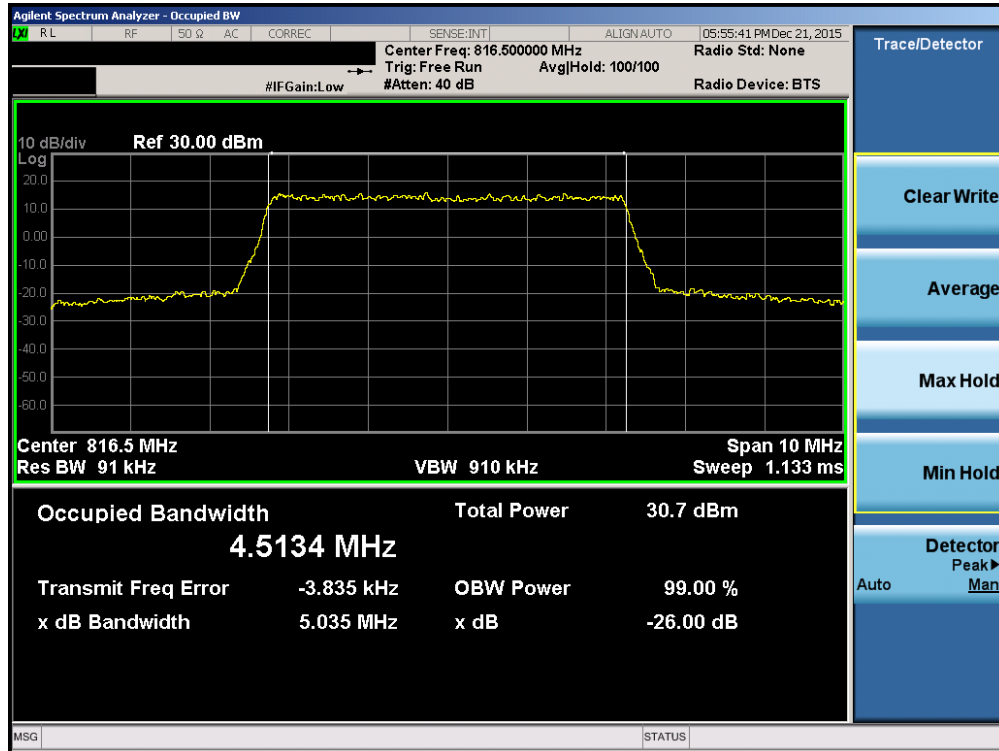


Plot 7-5. Occupied Bandwidth Plot (LTE Band 26 3MHz QPSK – RB Size 15– Low Channel)

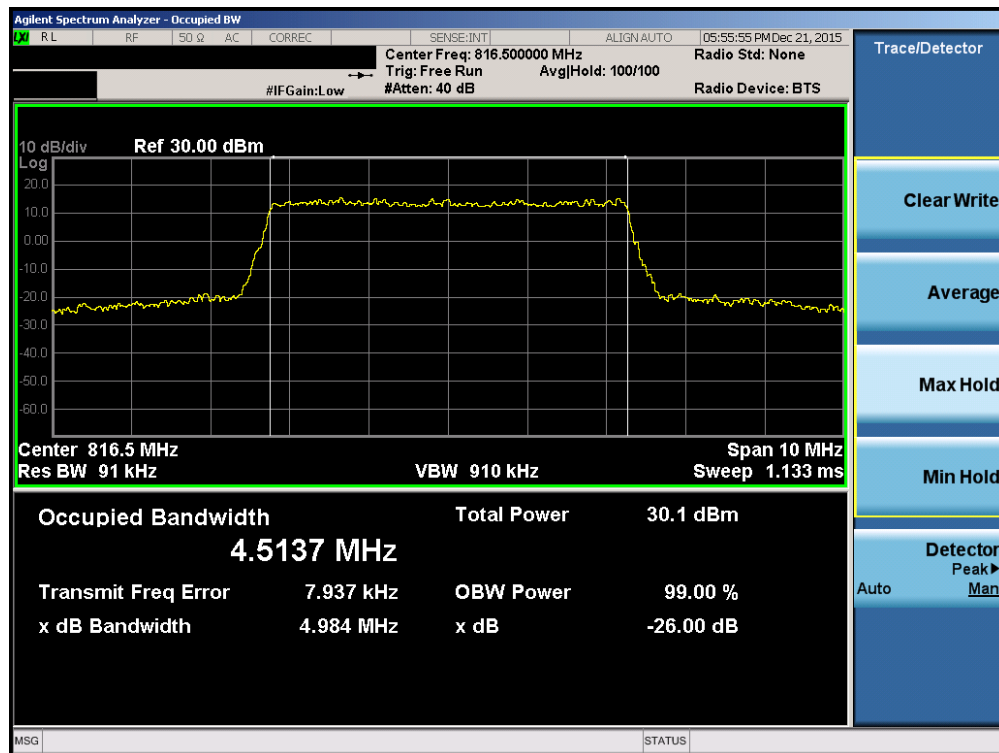


Plot 7-6. Occupied Bandwidth Plot (LTE Band 26 3MHz 16-QAM – RB Size 15– Low Channel)

FCC ID: A3LSMJ700P	PCTEST ENGINEERING LABORATORY, INC.	Part 90 CDMA / EvDo / LTE MEASUREMENT REPORT CERTIFICATION	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1512032049.A3L	Test Dates: 12/4/2015-1/15/2016	EUT Type: Portable Handset		Page 16 of 40

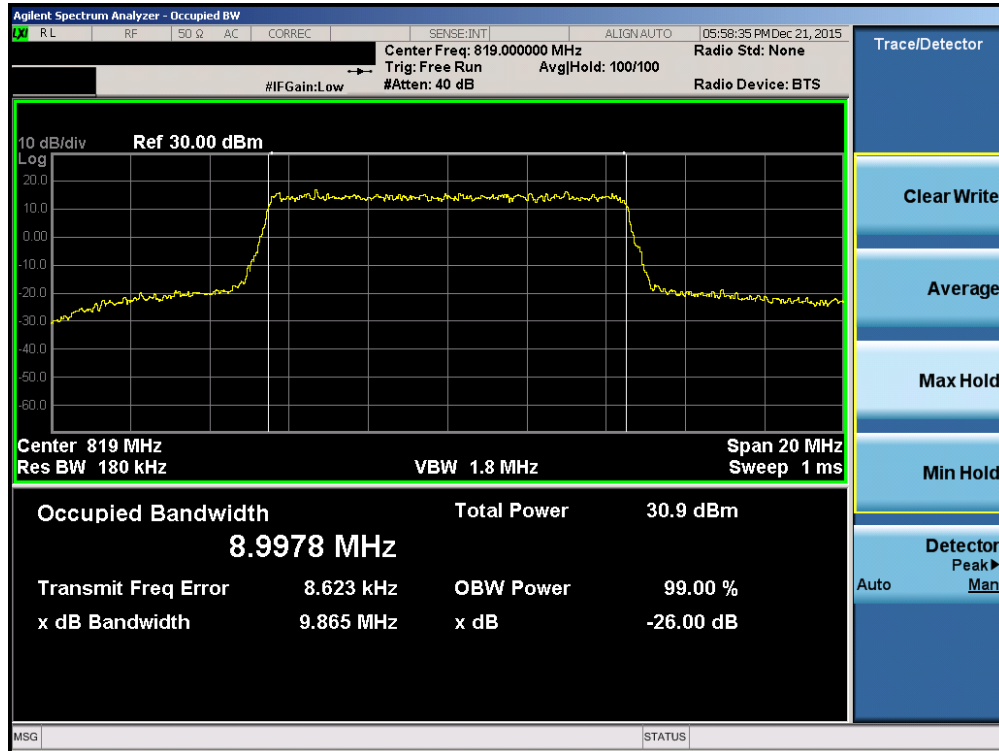


Plot 7-7. Occupied Bandwidth Plot (LTE Band 26 5MHz QPSK – RB Size 25– Low Channel)

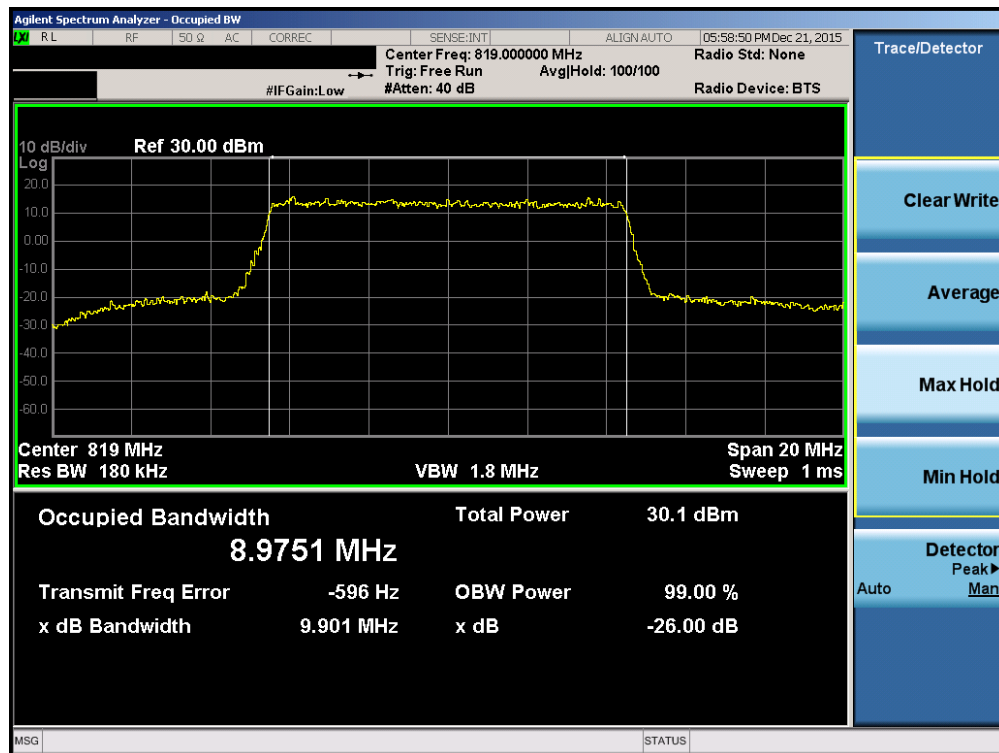


Plot 7-8. Occupied Bandwidth Plot (LTE Band 26 5MHz 16-QAM – RB Size 25– Low Channel)

FCC ID: A3LSMJ700P	PCTEST ENGINEERING LABORATORY, INC.	Part 90 CDMA / EvDO / LTE MEASUREMENT REPORT CERTIFICATION	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1512032049.A3L	Test Dates: 12/4/2015-1/15/2016	EUT Type: Portable Handset		Page 17 of 40



Plot 7-9. Occupied Bandwidth Plot (LTE Band 26 10MHz QPSK – RB Size 50)



Plot 7-10. Occupied Bandwidth Plot (LTE Band 26 10MHz 16-QAM – RB Size 50)

FCC ID: A3LSMJ700P	PCTEST ENGINEERING LABORATORY, INC.	Part 90 CDMA / EvDO / LTE MEASUREMENT REPORT CERTIFICATION	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1512032049.A3L	Test Dates: 12/4/2015-1/15/2016	EUT Type: Portable Handset		Page 18 of 40

7.3 Spurious and Harmonic Emissions at Antenna Terminal

§2.1051 §90.691

Test Overview

The level of the carrier and the various conducted spurious and harmonic frequencies is measured by means of a calibrated spectrum analyzer. The spectrum is scanned from the lowest frequency generated in the equipment up to a frequency including its 10th harmonic. All out of band emissions are measured with a spectrum analyzer connected to the antenna terminal of the EUT while the EUT is operating at maximum power, and at the appropriate frequencies. All data rates were investigated to determine the worst case configuration. All modes of operation were investigated and the worst case configuration results are reported in this section.

The minimum permissible attenuation level of any spurious emission is $43 + \log_{10}(P_{[Watts]})$, where P is the transmitter power in Watts.

Test Procedure Used

KDB 971168 D01 v02r02 – Section 6.0

Test Settings

1. Start frequency was set to 30MHz and stop frequency was set to 10GHz (separated into at least two plots per channel)
2. RBW $\geq$ 1MHz
3. VBW $\geq$ 3 x RBW
4. Detector = RMS
5. Trace mode = max hold
6. Sweep time = auto couple
7. The trace was allowed to stabilize

Test Setup

The EUT and measurement equipment were set up as shown in the diagram below.

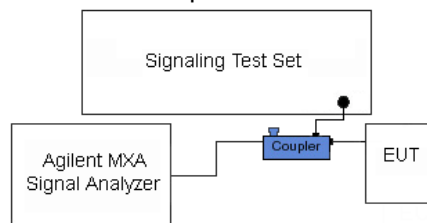
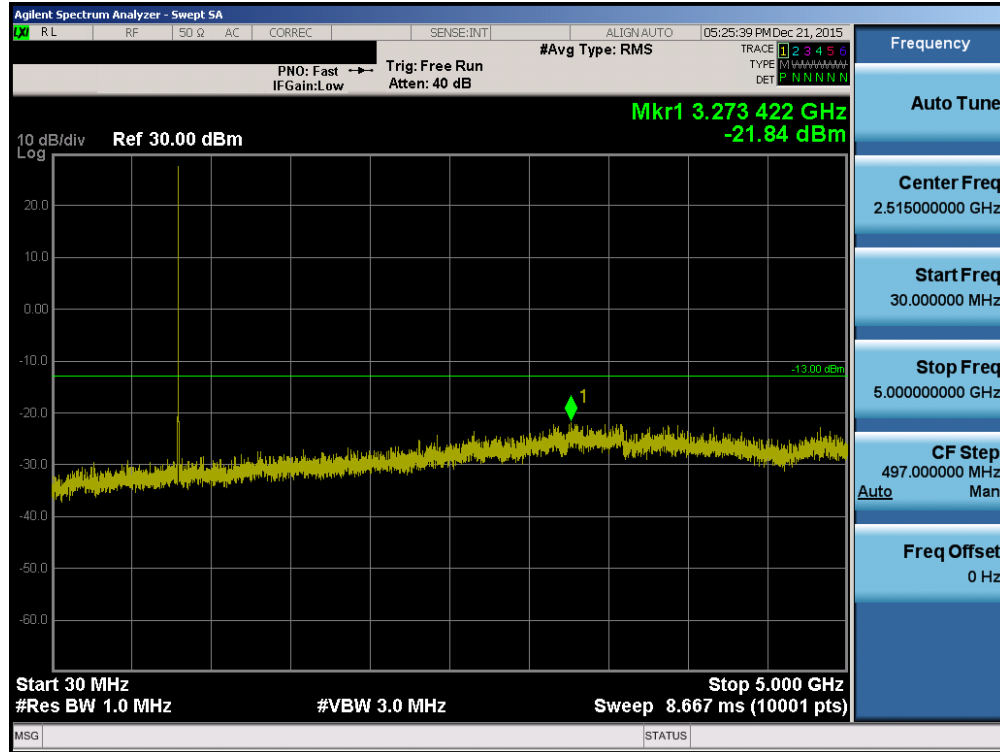


Figure 7-2. Test Instrument & Measurement Setup

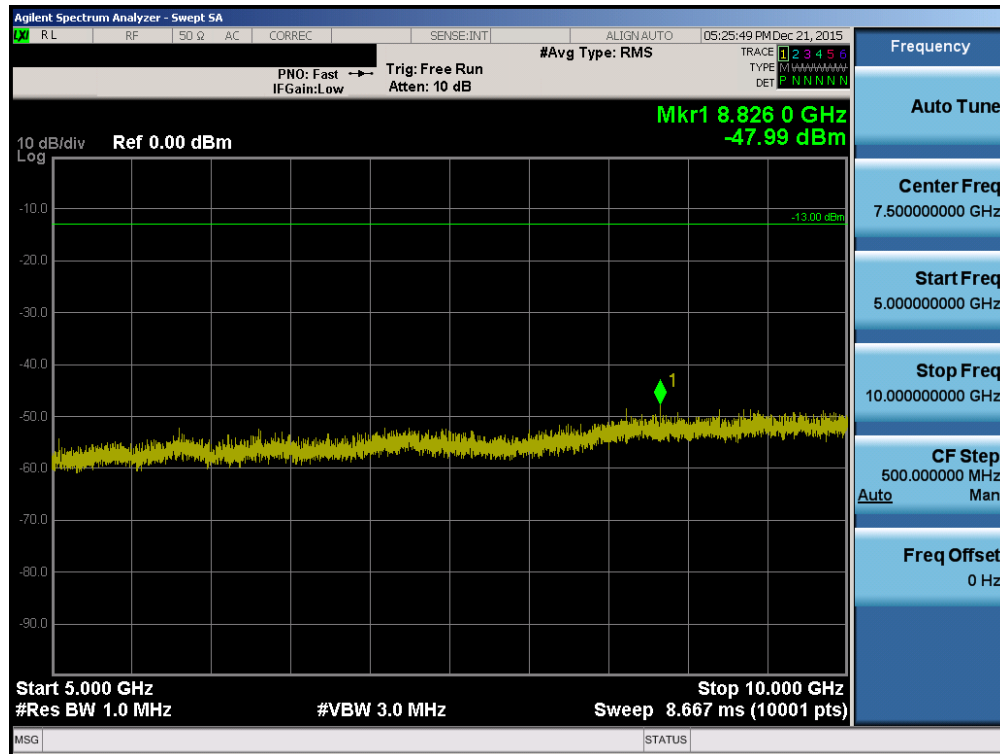
Test Notes

None.

FCC ID: A3LSMJ700P	PCTEST ENGINEERING LABORATORY, INC.	Part 90 CDMA / EvDO / LTE MEASUREMENT REPORT CERTIFICATION	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1512032049.A3L	Test Dates: 12/4/2015-1/15/2016	EUT Type: Portable Handset		Page 19 of 40

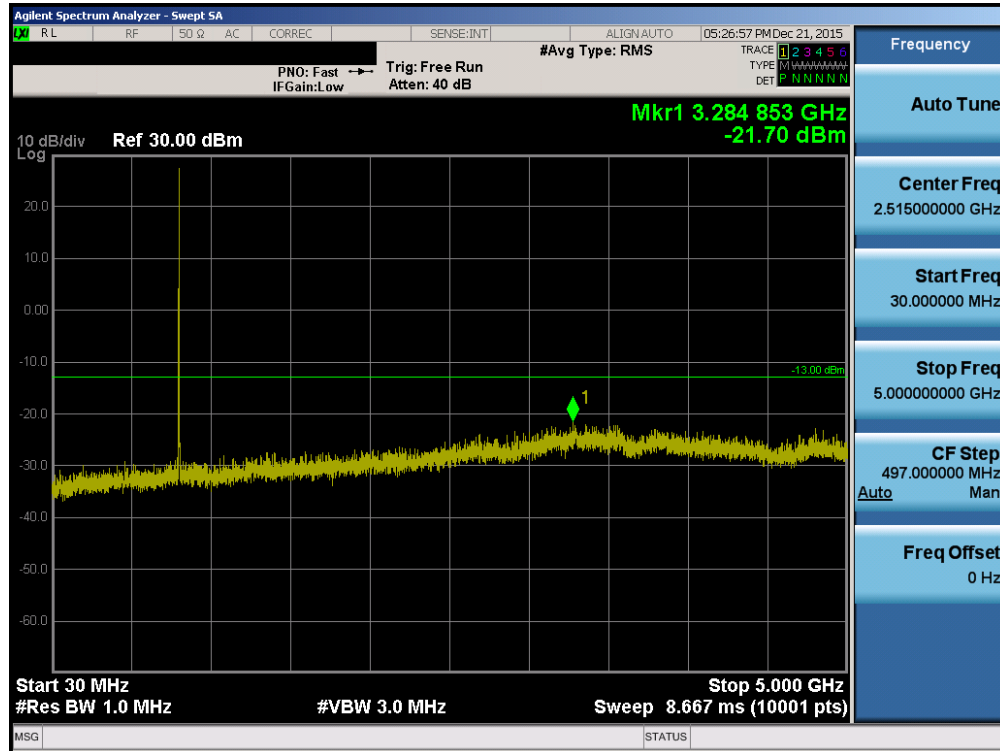


Plot 7-11. Conducted Spurious Plot (CDMA Ch. 476)

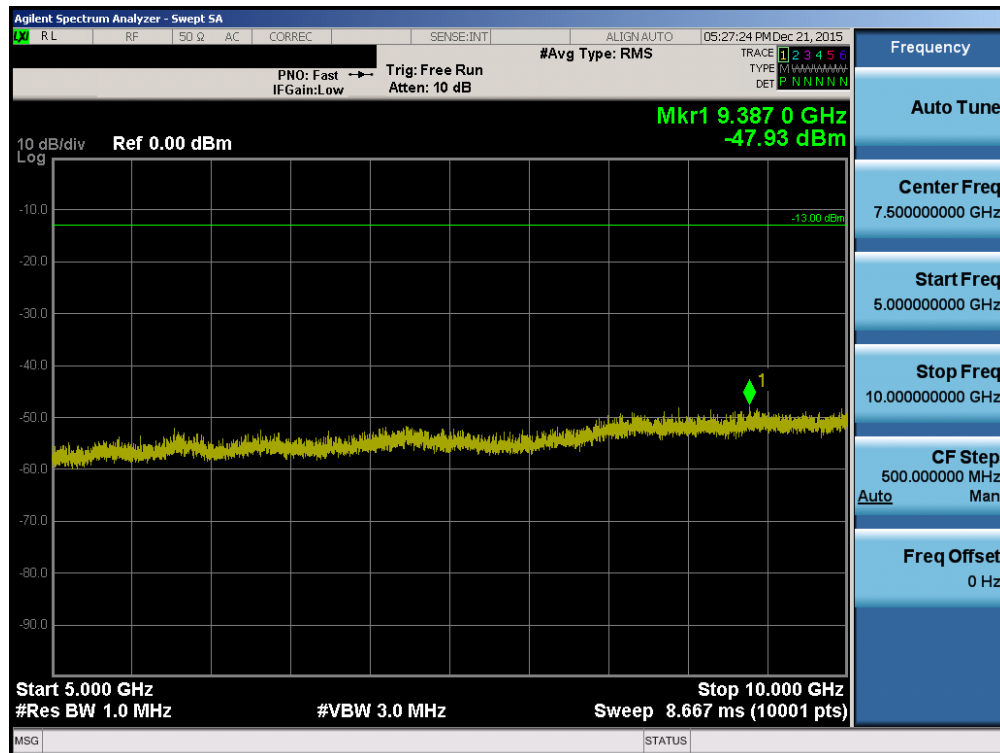


Plot 7-12. Conducted Spurious Plot (CDMA Ch. 476)

FCC ID: A3LSMJ700P	PCTEST ENGINEERING LABORATORY, INC.	Part 90 CDMA / EvDO / LTE MEASUREMENT REPORT CERTIFICATION	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1512032049.A3L	Test Dates: 12/4/2015-1/15/2016	EUT Type: Portable Handset		Page 20 of 40

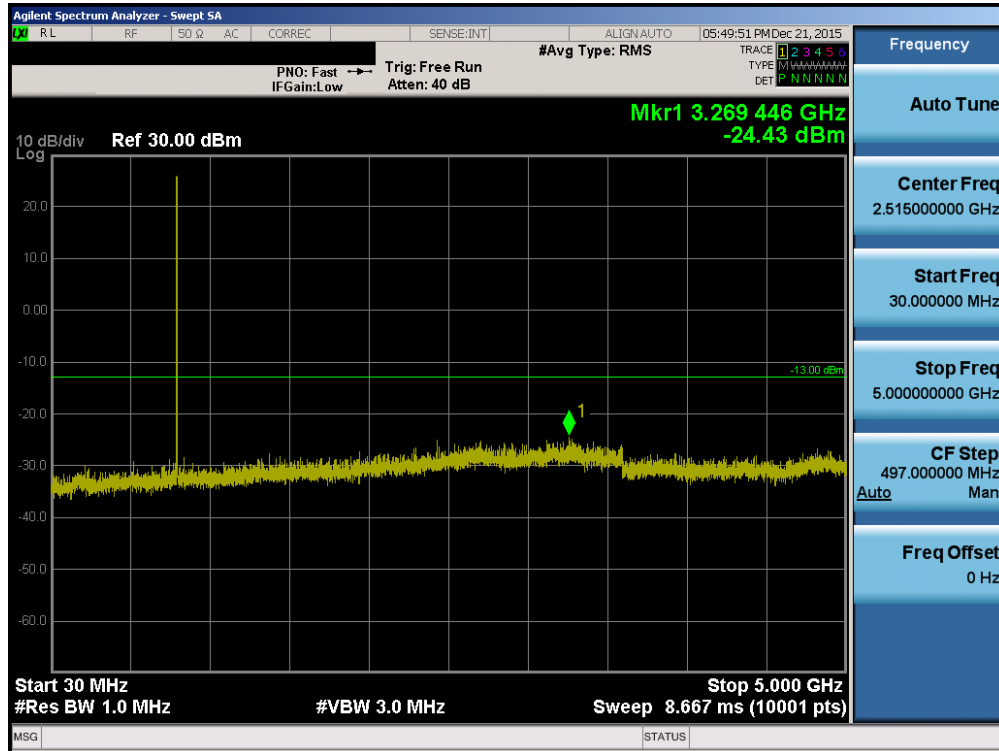


Plot 7-13. Conducted Spurious Plot (CDMA Ch. 684)

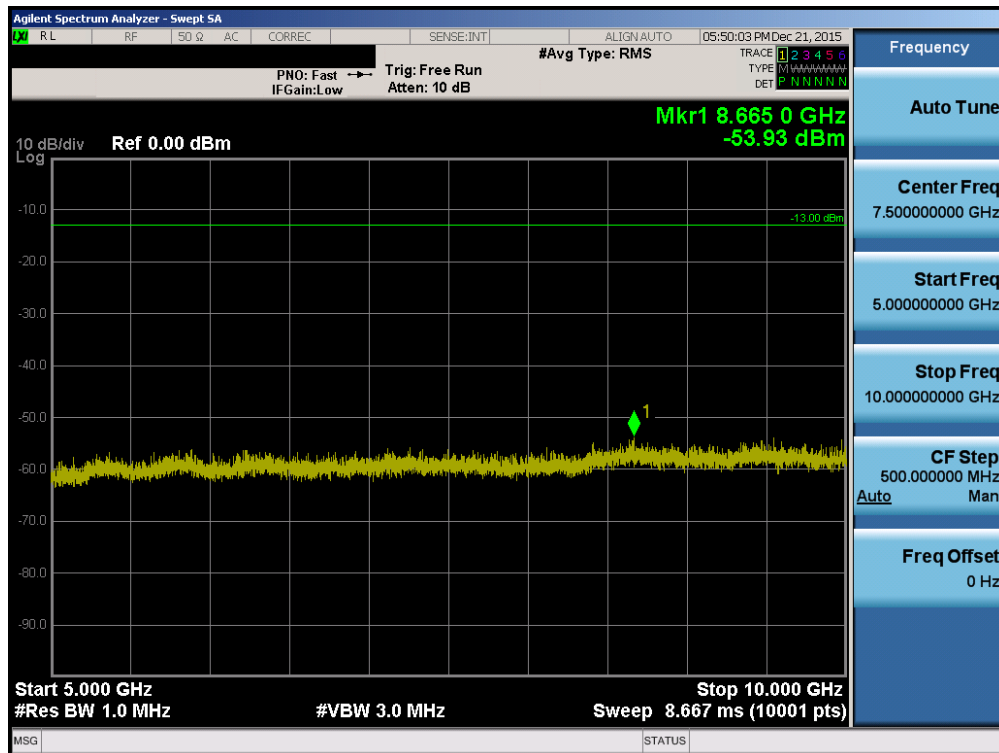


Plot 7-14. Conducted Spurious Plot (CDMA Ch. 684)

FCC ID: A3LSMJ700P	PCTEST ENGINEERING LABORATORY, INC.	Part 90 CDMA / EvDO / LTE MEASUREMENT REPORT CERTIFICATION	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1512032049.A3L	Test Dates: 12/4/2015-1/15/2016	EUT Type: Portable Handset		Page 21 of 40

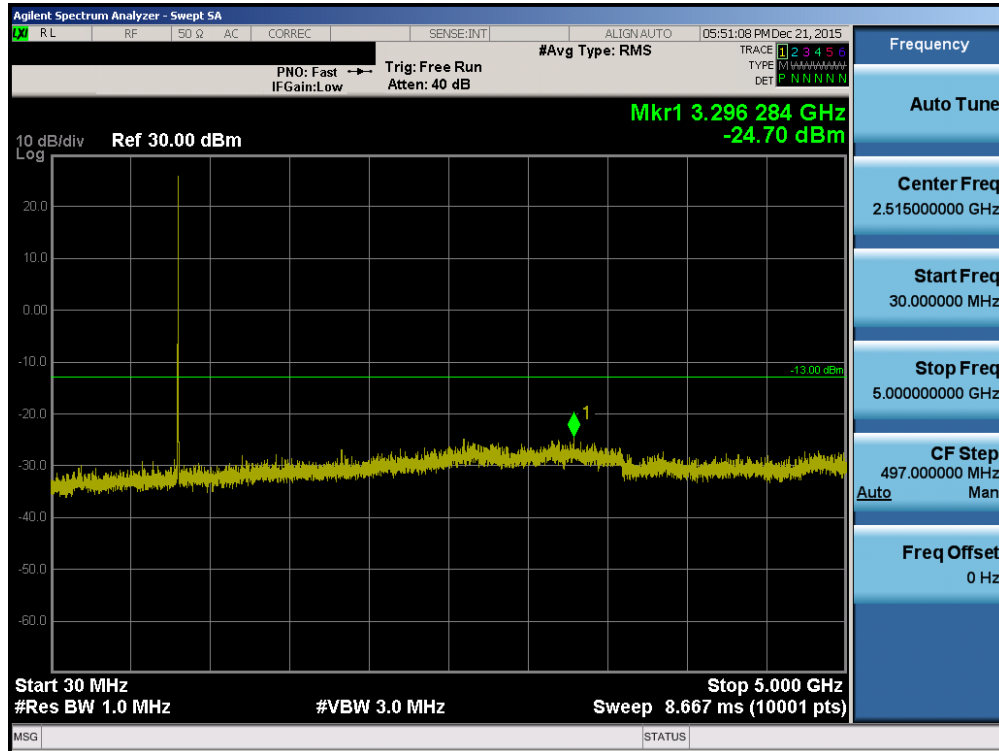


Plot 7-15. Conducted Spurious Plot (LTE Band 26 10MHz QPSK – RB Size 1, RB Offset 0 – Low Channel)

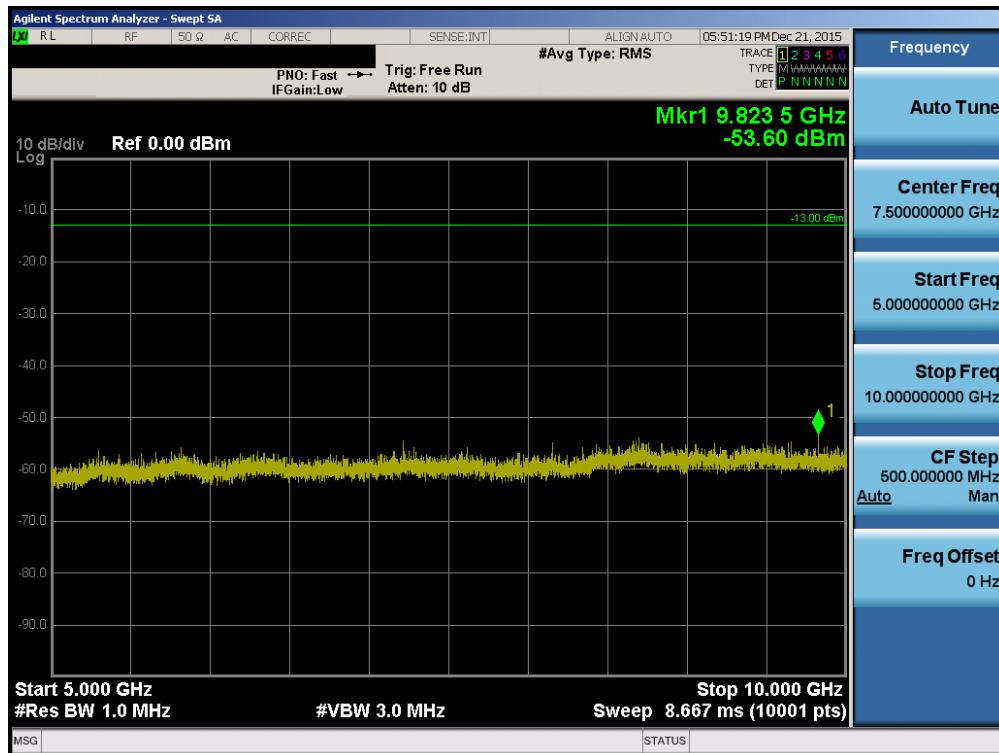


Plot 7-16. Conducted Spurious Plot (LTE Band 26 10MHz QPSK – RB Size 1, RB Offset 0 – Low Channel)

FCC ID: A3LSMJ700P	PCTEST ENGINEERING LABORATORY, INC.	Part 90 CDMA / EvDO / LTE MEASUREMENT REPORT CERTIFICATION	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1512032049.A3L	Test Dates: 12/4/2015-1/15/2016	EUT Type: Portable Handset		Page 22 of 40



Plot 7-17. Conducted Spurious Plot (LTE Band 26 10MHz QPSK – RB Size 1, RB Offset 0 – High Channel)



Plot 7-18. Conducted Spurious Plot (LTE Band 26 10MHz QPSK – RB Size 1, RB Offset 0 – High Channel)

FCC ID: A3LSMJ700P	PCTEST ENGINEERING LABORATORY, INC.	Part 90 CDMA / EvDO / LTE MEASUREMENT REPORT CERTIFICATION	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1512032049.A3L	Test Dates: 12/4/2015-1/15/2016	EUT Type: Portable Handset		Page 23 of 40

7.4 Band Edge Emissions at Antenna Terminal

~~\$2.1051~~ ~~\$90.691~~

Test Overview

All out of band emissions are measured with a spectrum analyzer connected to the antenna terminal of the EUT while the EUT is operating at maximum power, and at the appropriate frequencies. All data rates were investigated to determine the worst case configuration. All modes of operation were investigated and the worst case configuration results are reported in this section.

The minimum permissible attenuation level of any spurious emission removed from the EA licensee's frequency block by greater than 37.5 kHz is $43 + \log_{10}(P_{\text{Watts}})$, where P is the transmitter power in Watts.

The minimum permissible attenuation level of any spurious emission removed from the EA licensee's frequency block by up to and including 37.5 kHz is $50 + 10 \log_{10}(P_{\text{Watts}})$, where P is the transmitter power in Watts.

Test Procedure Used

KDB 971168 D01 v02r02 – Section 6.0

Test Settings

1. Span was set large enough so as to capture all out of band emissions near the band edge
2. RBW = 100 kHz
3. VBW = 300 kHz
4. Detector = RMS
5. Trace mode = trace average
6. Sweep time = auto couple
7. The trace was allowed to stabilize

Test Setup

The EUT and measurement equipment were set up as shown in the diagram below.

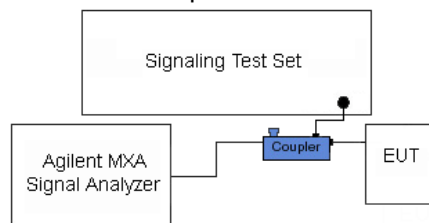
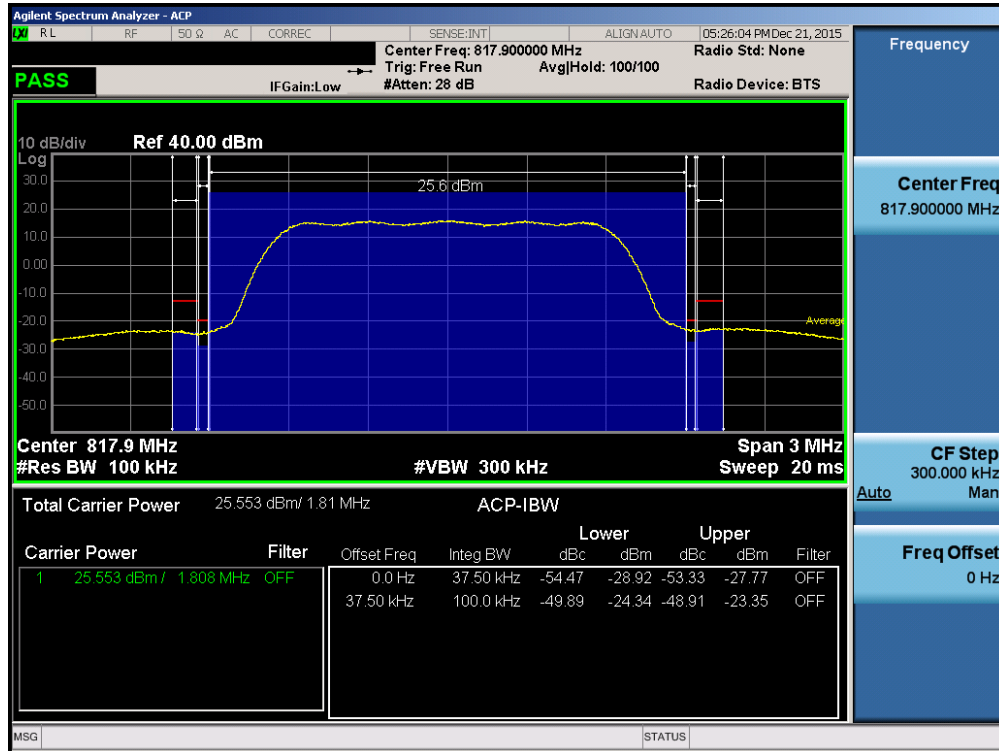


Figure 7-3. Test Instrument & Measurement Setup

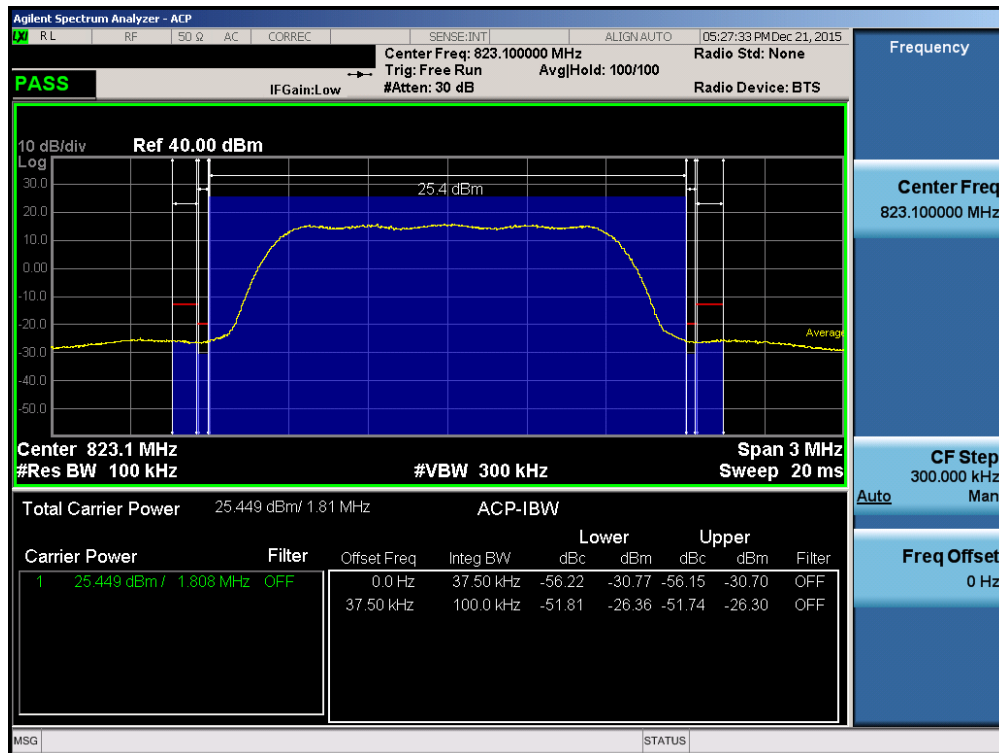
Test Notes

For channel edge emission, the signal analyzer's "ACP" measurement capability is used.

FCC ID: A3LSMJ700P	PCTEST ENGINEERING LABORATORY, INC.	Part 90 CDMA / EvDO / LTE MEASUREMENT REPORT CERTIFICATION	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1512032049.A3L	Test Dates: 12/4/2015-1/15/2016	EUT Type: Portable Handset		Page 24 of 40

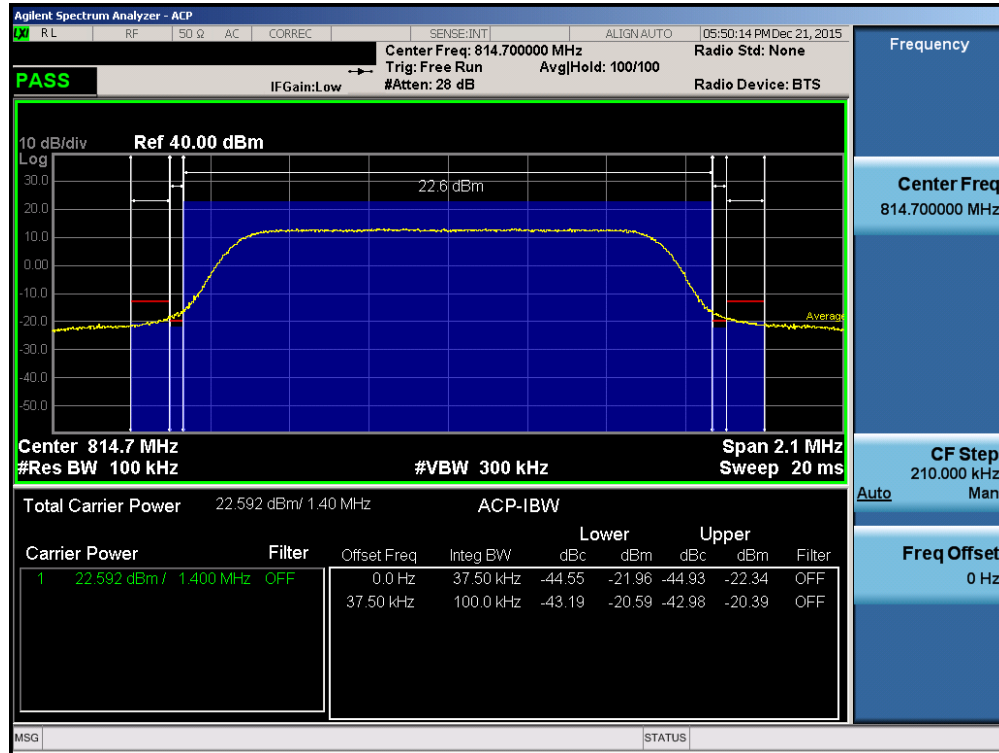


Plot 7-19. Channel Edge Plot (CDMA Ch. 476)

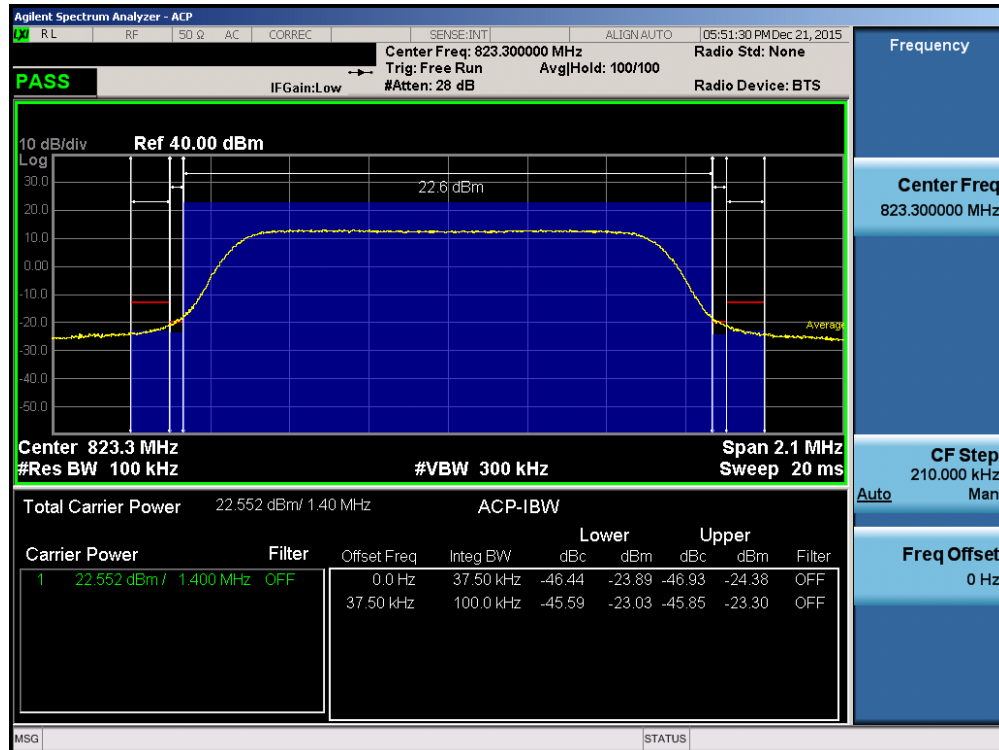


Plot 7-20. Channel Edge Plot (CDMA Ch. 684)

FCC ID: A3LSMJ700P	PCTEST ENGINEERING LABORATORY, INC.	Part 90 CDMA / EvDo / LTE MEASUREMENT REPORT CERTIFICATION	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1512032049.A3L	Test Dates: 12/4/2015-1/15/2016	EUT Type: Portable Handset		Page 25 of 40

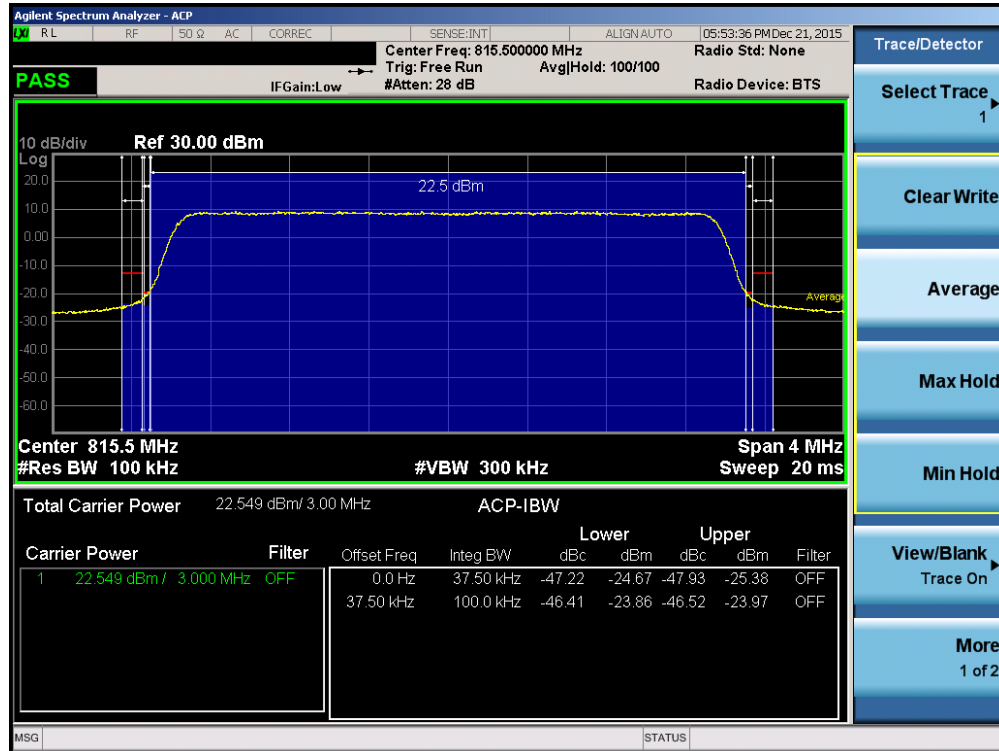


Plot 7-21. Channel Edge Plot (LTE Band 26 1.4MHz QPSK – RB Size 6– Low Channel)

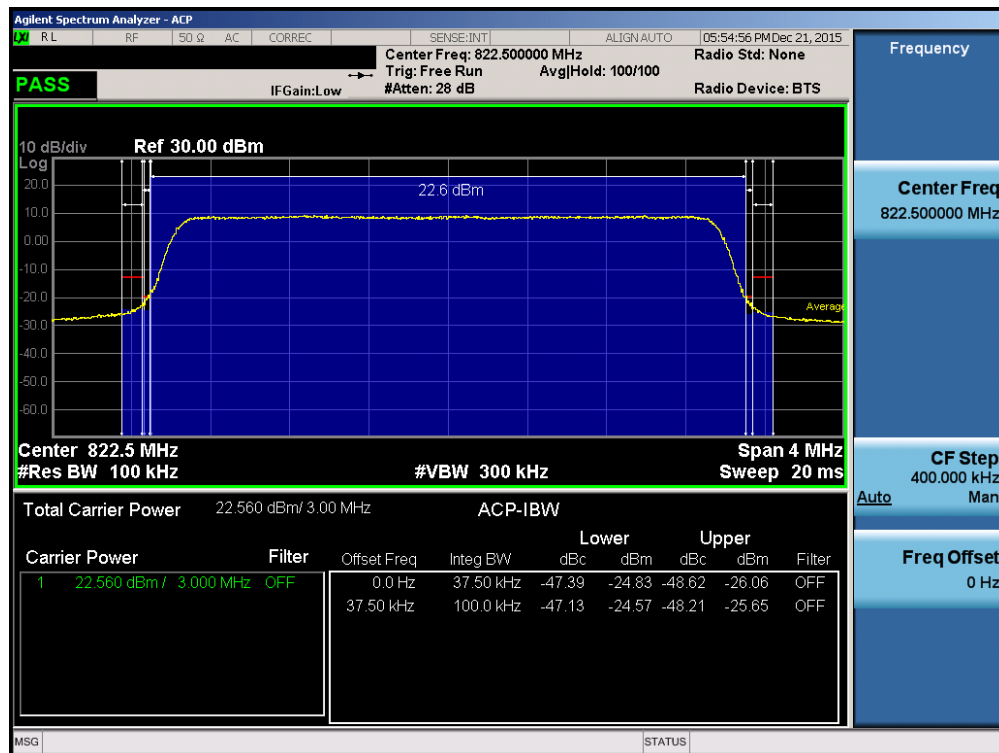


Plot 7-22. Channel Edge Plot (LTE Band 26 1.4MHz QPSK – RB Size 6 – High Channel)

FCC ID: A3LSMJ700P	PCTEST ENGINEERING LABORATORY, INC.	Part 90 CDMA / EvDO / LTE MEASUREMENT REPORT CERTIFICATION	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1512032049.A3L	Test Dates: 12/4/2015-1/15/2016	EUT Type: Portable Handset		Page 26 of 40

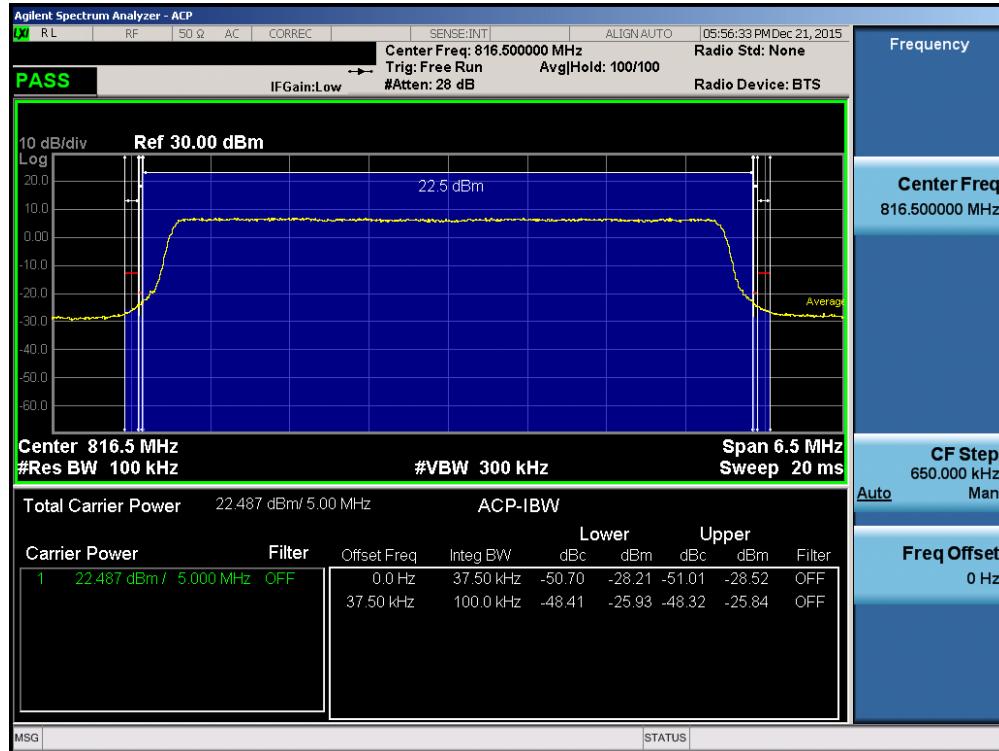


Plot 7-23. Channel Edge Plot (LTE Band 26 3MHz QPSK – RB Size 15– Low Channel)

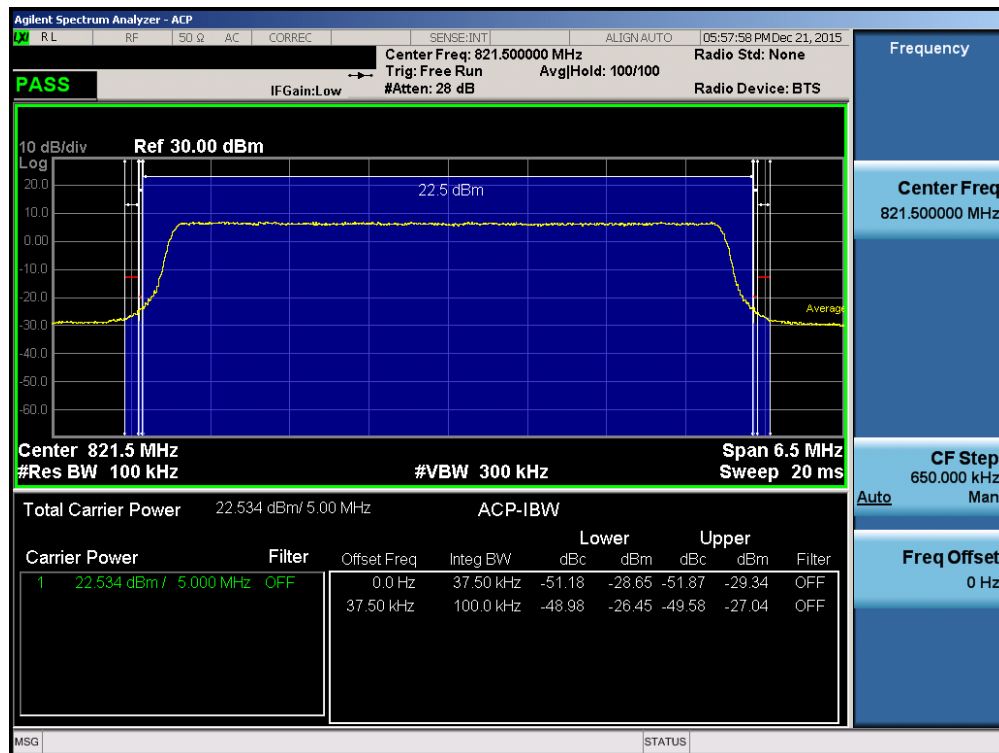


Plot 7-24. Channel Edge Plot (LTE Band 26 3MHz QPSK – RB Size 15 – High Channel)

FCC ID: A3LSMJ700P	PCTEST ENGINEERING LABORATORY, INC.	Part 90 CDMA / EvDO / LTE MEASUREMENT REPORT CERTIFICATION	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1512032049.A3L	Test Dates: 12/4/2015-1/15/2016	EUT Type: Portable Handset		Page 27 of 40

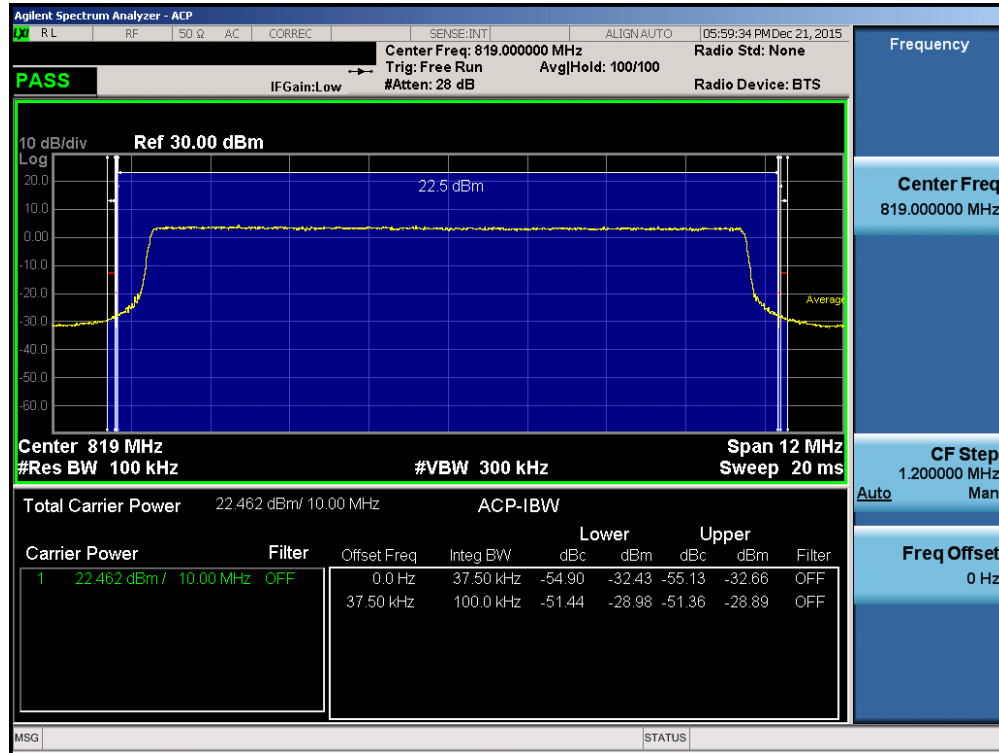


Plot 7-25. Channel Edge Plot (LTE Band 26 5MHz QPSK – RB Size 25– Low Channel)



Plot 7-26. Channel Edge Plot (LTE Band 26 5MHz QPSK – RB Size 25 – High Channel)

FCC ID: A3LSMJ700P	PCTEST ENGINEERING LABORATORY, INC.	Part 90 CDMA / EvDo / LTE MEASUREMENT REPORT CERTIFICATION	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1512032049.A3L	Test Dates: 12/4/2015-1/15/2016	EUT Type: Portable Handset		Page 28 of 40



Plot 7-27. Channel Edge Plot (LTE Band 26 10MHz QPSK – RB Size 50)

FCC ID: A3LSMJ700P	PCTEST ENGINEERING LABORATORY, INC.	Part 90 CDMA / EvDO / LTE MEASUREMENT REPORT CERTIFICATION	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1512032049.A3L	Test Dates: 12/4/2015-1/15/2016	EUT Type: Portable Handset		Page 29 of 40

7.5 Conducted Power Output Data

§90.635

Frequency [MHz]	BC10 [Channel]	Battery Type	Cond. PWR [dBm]	Cond. PWR [Watts]	Cond. PWR Limit [dBm]	Margin [dB]
817.90	476	Standard	24.92	0.310	50.00	-25.08
823.10	684	Standard	25.00	0.316	50.00	-25.00

Table 7-2. CDMA BC10 Conducted Power Output Data

Frequency [MHz]	Channel Bandwidth [MHz]	Mod.	Cond. PWR [dBm]	Cond. PWR [Watts]	Cond. PWR Limit [dBm]	Margin [dB]
814.70	1.4	QPSK	23.68	0.233	50.00	-26.32
823.30	1.4	QPSK	23.84	0.242	50.00	-26.16
814.70	1.4	16-QAM	23	0.200	50.00	-27.00
823.30	1.4	16-QAM	22.76	0.189	50.00	-27.24
815.50	3	QPSK	23.85	0.243	50.00	-26.15
822.50	3	QPSK	23.85	0.243	50.00	-26.15
815.50	3	16-QAM	22.92	0.196	50.00	-27.08
822.50	3	16-QAM	22.89	0.195	50.00	-27.11
816.50	5	QPSK	23.44	0.221	50.00	-26.56
821.50	5	QPSK	23.89	0.245	50.00	-26.11
816.50	5	16-QAM	22.45	0.176	50.00	-27.55
821.50	5	16-QAM	22.93	0.196	50.00	-27.07
819.00	10	QPSK	23.89	0.245	50.00	-26.11
819.00	10	16-QAM	23.00	0.200	50.00	-27.00

Table 7-3. LTE Band 26 Conducted Power Output Data

NOTES:

- For CDMA mode, this device was tested under all R.C.s and S.O.s and the worst case is reported with RC3/SO55 with "All Up" power control bits. For LTE mode, the device was tested under all modulations, RB sizes and offsets, and channel bandwidth configurations and the worst case emissions are reported with 1 RB.
- This unit was tested with its standard battery.

FCC ID: A3LSMJ700P		Part 90 CDMA / EvDO / LTE MEASUREMENT REPORT CERTIFICATION		Reviewed by: Quality Manager
Test Report S/N: 0Y1512032049.A3L	Test Dates: 12/4/2015-1/15/2016	EUT Type: Portable Handset		Page 30 of 40

7.6 Radiated Spurious Emissions Measurements

\$2.1053, \$90.691

Test Overview

Radiated spurious emissions measurements are performed using the substitution method described in ANSI/TIA-603-C-2004 with the EUT transmitting into an integral antenna. Measurements on signals operating below 1GHz are performed using horizontally and vertically polarized tuned dipole antennas. Measurements on signals operating above 1GHz are performed using vertically and horizontally polarized broadband horn antennas. All measurements are performed as peak measurements while the EUT is operating at maximum power, and at the appropriate frequencies.

Test Procedures Used

KDB 971168 D01 v02r02 – Section 5.8

ANSI/TIA-603-C-2004 – Section 2.2.12

Test Settings

1. RBW = 100kHz for emissions below 1GHz and 1MHz for emissions above 1GHz
2. VBW $\geq 3 \times$ RBW
3. Span = 1.5 times the OBW
4. No. of sweep points $\geq 2 \times$ span / RBW
5. Detector = Peak
6. Trace mode = max hold
7. The trace was allowed to stabilize

FCC ID: A3LSMJ700P		Part 90 CDMA / EvDO / LTE MEASUREMENT REPORT CERTIFICATION		Reviewed by: Quality Manager
Test Report S/N: 0Y1512032049.A3L	Test Dates: 12/4/2015-1/15/2016	EUT Type: Portable Handset		Page 31 of 40

Test Setup

The EUT and measurement equipment were set up as shown in the diagram below.

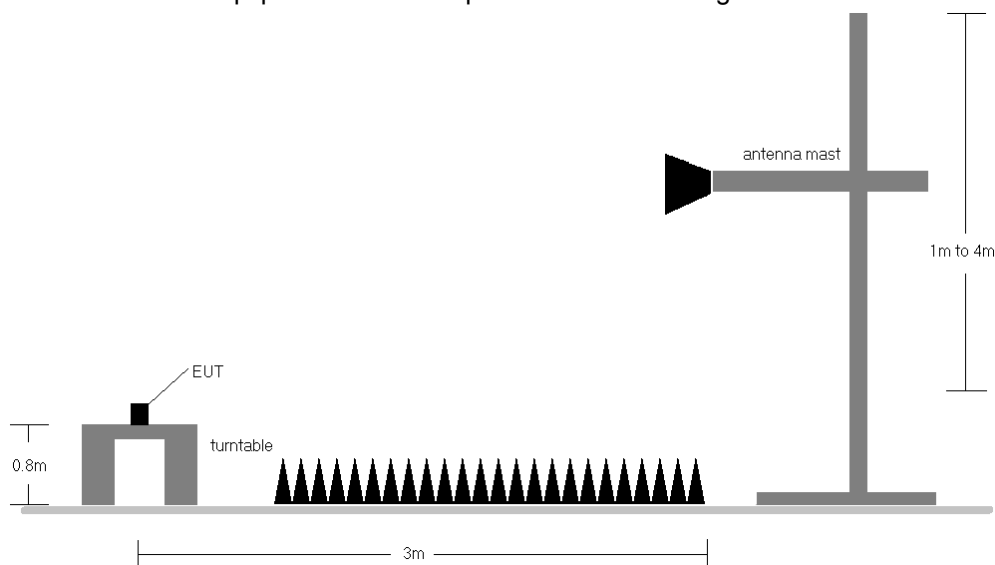


Figure 7-4. Test Instrument & Measurement Setup

Test Notes

1. For CDMA mode, this device was tested under all R.C.s and S.O.s and the worst case is reported with RC3/SO55 with "All Up" power control bits.
2. For LTE mode, the device was tested under all modulations, RB sizes and offsets, and channel bandwidth configurations and the worst case emissions are reported with 1 RB.
3. This unit was tested with its standard battery.
4. The EUT was tested in three orthogonal planes and in all possible test configurations and positioning. The worst case setup is reported in the tables below.

FCC ID: A3LSMJ700P	PCTEST ENGINEERING LABORATORY, INC.	Part 90 CDMA / EvDO / LTE MEASUREMENT REPORT CERTIFICATION	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1512032049.A3L	Test Dates: 12/4/2015-1/15/2016	EUT Type: Portable Handset		Page 32 of 40

OPERATING FREQUENCY: 817.90 MHz
 CHANNEL: 476
 MEASURED OUTPUT POWER: 24.92 dBm = 0.310 W
 MODULATION SIGNAL: CDMA
 DISTANCE: 3 meters
 LIMIT: $43 + 10 \log_{10} (W) =$ -13.00 dBm

Frequency [MHz]	Ant. Pol. [H/V]	Antenna Height [m]	Turntable Azimuth [degree]	Level at Antenna Terminals [dBm]	Substitute Antenna Gain [dBd]	Spurious Emission Level [dBm]	Margin [dB]
1635.80	V	1.00	69	-48.85	3.64	-45.20	-32.2
2453.70	V	1.00	360	-53.56	3.55	-50.00	-37.0

Table 7-4. CDMA BC10 Radiated Spurious Data (Ch. 476)

OPERATING FREQUENCY: 823.10 MHz
 CHANNEL: 684
 MEASURED OUTPUT POWER: 25.00 dBm = 0.316 W
 MODULATION SIGNAL: CDMA
 DISTANCE: 3 meters
 LIMIT: $43 + 10 \log_{10} (W) =$ -13.00 dBm

Frequency [MHz]	Ant. Pol. [H/V]	Antenna Height [m]	Turntable Azimuth [degree]	Level at Antenna Terminals [dBm]	Substitute Antenna Gain [dBd]	Spurious Emission Level [dBm]	Margin [dB]
1646.20	V	1.00	70	-53.38	3.60	-49.78	-36.8
2469.30	V	1.00	360	-54.21	3.54	-50.67	-37.7

Table 7-5. CDMA BC10 Radiated Spurious Data (Ch. 684)

OPERATING FREQUENCY: 816.50 MHz
 CHANNEL: 26715
 MEASURED OUTPUT POWER: 23.44 dBm = 0.221 W
 MODULATION SIGNAL: QPSK
 BANDWIDTH: 5.0 MHz
 DISTANCE: 3 meters
 LIMIT: $43 + 10 \log_{10} (W) =$ -13.00 dBm

Frequency [MHz]	Ant. Pol. [H/V]	Antenna Height [m]	Turntable Azimuth [degree]	Level at Antenna Terminals [dBm]	Substitute Antenna Gain [dBd]	Spurious Emission Level [dBm]	Margin [dB]
1633.00	V	1.00	230	-42.81	3.66	-39.15	-26.2
2449.50	V	1.00	0	-52.72	3.56	-49.16	-36.2

Table 7-6. LTE Band 26 Radiated Spurious Data (Ch. 26715)

OPERATING FREQUENCY: 821.50 MHz
 CHANNEL: 26765
 MEASURED OUTPUT POWER: 23.89 dBm = 0.245 W
 MODULATION SIGNAL: QPSK
 BANDWIDTH: 5.0 MHz
 DISTANCE: 3 meters
 LIMIT: $43 + 10 \log_{10} (W) =$ -13.00 dBm

Frequency [MHz]	Ant. Pol. [H/V]	Antenna Height [m]	Turntable Azimuth [degree]	Level at Antenna Terminals [dBm]	Substitute Antenna Gain [dBd]	Spurious Emission Level [dBm]	Margin [dB]
1643.00	V	1.00	73	-53.07	3.62	-49.45	-36.4
2464.50	V	1.00	0	-48.32	3.54	-44.78	-31.8

Table 7-7. LTE Band 26 Radiated Spurious Data (Ch. 26765)

7.7 Frequency Stability / Temperature Variation

\$2.1055 \$90.213

Test Overview and Limit

Frequency stability testing is performed in accordance with the guidelines of ANSI/TIA-603-C-2004. The frequency stability of the transmitter is measured by:

- a.) **Temperature:** The temperature is varied from -30°C to +50°C in 10°C increments using an environmental chamber.
- b.) **Primary Supply Voltage:** The primary supply voltage is varied from 85% to 115% of the nominal value for non hand-carried battery and AC powered equipment. For hand-carried, battery-powered equipment, primary supply voltage is reduced to the battery operating end point which shall be specified by the manufacturer.

The frequency stability of the transmitter shall be maintained within $\pm 0.00025\%$ (± 2.5 ppm) of the center frequency.

Test Procedure Used

ANSI/TIA-603-C-2004

Test Settings

1. The carrier frequency of the transmitter is measured at room temperature (20°C to provide a reference).
2. The equipment is turned on in a “standby” condition for fifteen minutes before applying power to the transmitter. Measurement of the carrier frequency of the transmitter is made within one minute after applying power to the transmitter.
3. Frequency measurements are made at 10°C intervals ranging from -30°C to +50°C. A period of at least one half-hour is provided to allow stabilization of the equipment at each temperature level.

Test Setup

The EUT was connected via an RF cable to a spectrum analyzer with the EUT placed inside an environmental chamber.

Test Notes

None

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Frequency Stability / Temperature Variation

§2.1055, §90.213

OPERATING FREQUENCY: 817,900,000 Hz
 CHANNEL: 476
 REFERENCE VOLTAGE: 3.80 VDC
 DEVIATION LIMIT: ± 0.00025 % or 2.5 ppm

VOLTAGE (%)	POWER (VDC)	TEMP (°C)	FREQUENCY (Hz)	Freq. Dev. (Hz)	Deviation (%)
100 %	3.80	+ 20 (Ref)	817,900,107	107	0.0000131
100 %		- 30	817,899,976	-24	-0.0000029
100 %		- 20	817,899,857	-143	-0.0000175
100 %		- 10	817,899,935	-65	-0.0000079
100 %		0	817,899,990	-10	-0.0000012
100 %		+ 10	817,900,104	104	0.0000127
100 %		+ 20	817,899,852	-148	-0.0000181
100 %		+ 30	817,899,982	-18	-0.0000022
100 %		+ 40	817,899,931	-69	-0.0000084
100 %		+ 50	817,900,077	77	0.0000094
BATT. ENDPOINT	3.40	+ 20	817,899,959	-41	-0.0000050

Table 7-8. CDMA BC10 Frequency Stability Data (Ch. 476)

FCC ID: A3LSMJ700P		Part 90 CDMA / EvDO / LTE MEASUREMENT REPORT CERTIFICATION		Reviewed by: Quality Manager
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Frequency Stability / Temperature Variation

§2.1055, §90.213

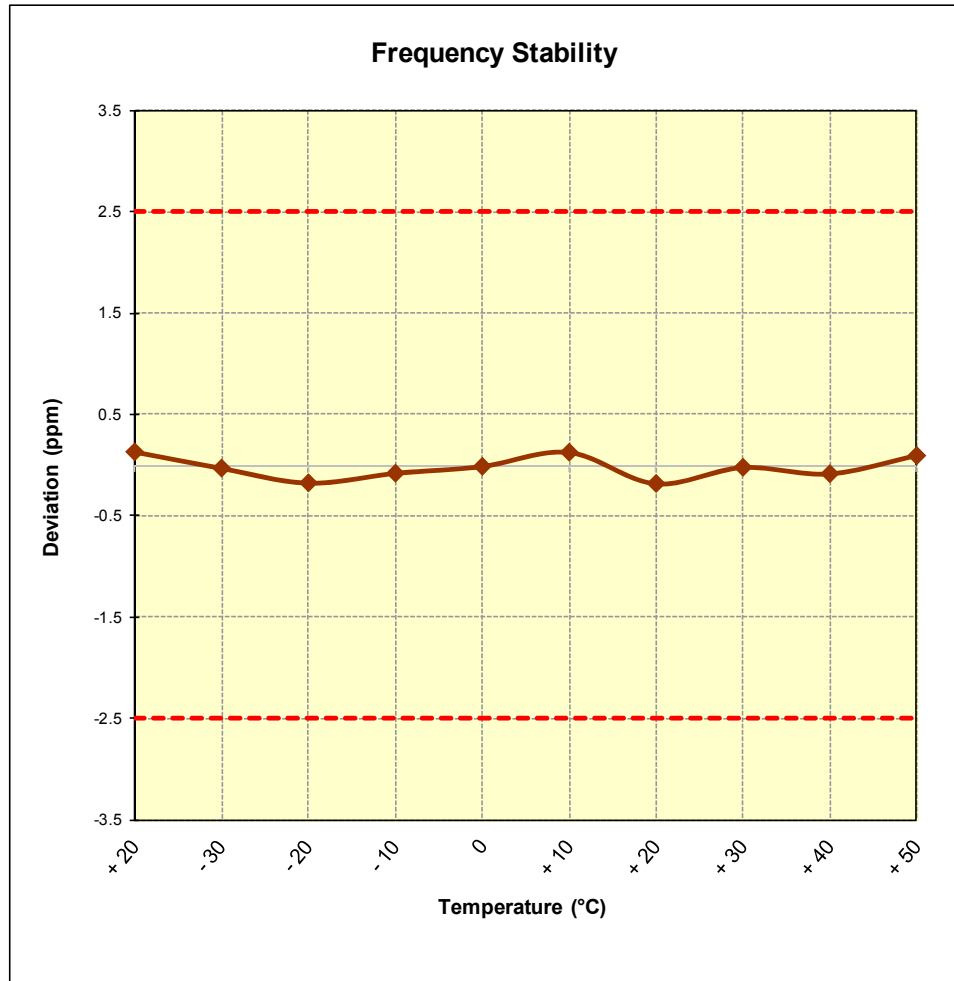


Figure 7-5. CDMA BC10 Frequency Stability Graph (Ch. 476)

FCC ID: A3LSMJ700P	PCTEST ENGINEERING LABORATORY, INC.	Part 90 CDMA / EvDO / LTE MEASUREMENT REPORT CERTIFICATION	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1512032049.A3L	Test Dates: 12/4/2015-1/15/2016	EUT Type: Portable Handset		Page 37 of 40

Frequency Stability / Temperature Variation

§2.1055, §90.213

OPERATING FREQUENCY: 816,500,000 Hz
 CHANNEL: 26715
 REFERENCE VOLTAGE: 3.80 VDC
 DEVIATION LIMIT: ± 0.00025 % or 2.5 ppm

VOLTAGE (%)	POWER (VDC)	TEMP (°C)	FREQUENCY (Hz)	Freq. Dev. (Hz)	Deviation (%)
100 %	3.80	+ 20 (Ref)	817,900,000	-124	-0.0000152
100 %		- 30	817,900,000	133	0.0000163
100 %		- 20	817,900,000	-72	-0.0000088
100 %		- 10	817,900,000	-101	-0.0000124
100 %		0	817,900,000	-108	-0.0000132
100 %		+ 10	817,900,000	-138	-0.0000169
100 %		+ 20	817,900,000	-115	-0.0000141
100 %		+ 30	817,900,000	30	0.0000037
100 %		+ 40	817,900,000	-121	-0.0000148
100 %		+ 50	817,900,000	-2	-0.0000002
BATT. ENDPOINT	3.40	+ 20	817,900,000	62	0.0000076

Table 7-9. LTE Band 26 Frequency Stability Data (Ch. 26715)

FCC ID: A3LSMJ700P		Part 90 CDMA / EvDO / LTE MEASUREMENT REPORT CERTIFICATION			Reviewed by: Quality Manager
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Frequency Stability / Temperature Variation

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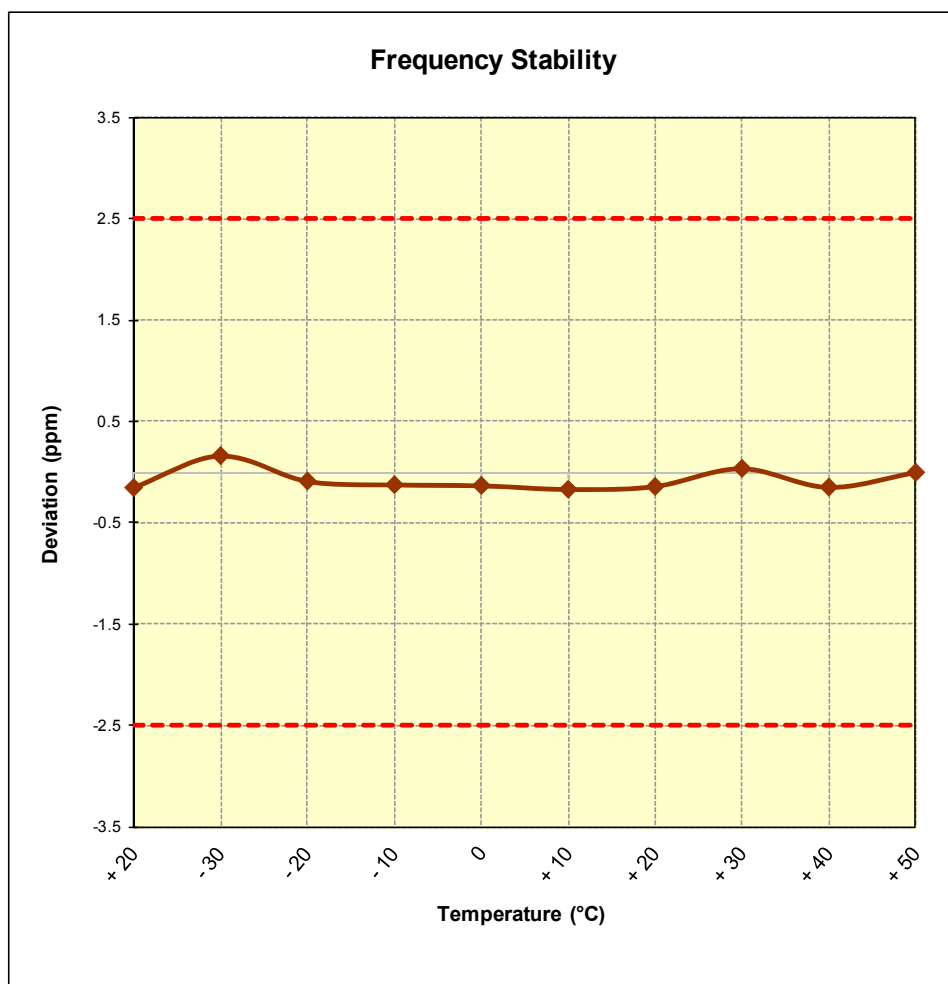


Table 7-10. LTE Band 26 Frequency Stability Data (Ch. 26715)

FCC ID: A3LSMJ700P		Part 90 CDMA / EvDO / LTE MEASUREMENT REPORT CERTIFICATION		Reviewed by: Quality Manager
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8.0 CONCLUSION

The data collected relate only to the item(s) tested and show that the **Samsung Portable Handset FCC ID: A3LSMJ700P** complies with all the requirements of Parts 90 of the FCC rules.

FCC ID: A3LSMJ700P		Part 90 CDMA / EvDO / LTE MEASUREMENT REPORT CERTIFICATION		Reviewed by: Quality Manager
Test Report S/N: 0Y1512032049.A3L	Test Dates: 12/4/2015-1/15/2016	EUT Type: Portable Handset	Page 40 of 40	